

LHCb-2005-105
ELECTRONICS
August 22, 2006

The Beetle Reference Manual

— chip version 1.3, 1.4 and 1.5 —

S. LÖCHNER*, M. SCHMELLING

— Max-Planck-Institute for Nuclear Physics, Heidelberg, Germany —

document version: 1.73

Abstract

This paper details the electrical specifications, operating conditions and port definitions of the readout chips *Beetle1.3*, *1.4* and *1.5*. The chip is developed for the LHCb experiment and fulfils the requirements of the silicon vertex detector (VELO, PUS¹), the silicon tracker and the RICH detectors in case of multi-anode photomultiplier readout.

It integrates 128 channels with low-noise charge-sensitive preamplifiers and shapers. The pulse shape can be chosen such that it complies with LHCb specifications: a peaking time of 25 ns with a remainder of the peak voltage after 25 ns of less than 30%. A comparator per channel with configurable polarity provides a binary signal. Four adjacent comparator channels are being ORed and brought off chip via LVDS ports. Either the shaper or comparator output is sampled with the LHC bunch-crossing frequency of 40 MHz into an analogue pipeline. This ring buffer has a programmable latency of max. 160 sampling intervals and an integrated derandomising buffer of 16 stages. For analogue readout data is multiplexed with up to 40 MHz onto 1 or 4 ports. A binary readout mode operates at up to 80 MHz output rate on two ports. Current drivers bring the serialised data off chip. The chip can accept trigger rates up to 1.1 MHz to perform a dead-timeless readout within 900 ns per trigger. For testability and calibration purposes, a charge injector with adjustable pulse height is implemented. The bias settings and various other parameters can be controlled via a standard I²C-interface.

Appropriate design measures have been taken to ensure the radiation hardness against total dose effects in excess of 100 Mrad. Robustness against Single Event Upset is achieved by redundant logic.

*Email: loechner@kip.uni-heidelberg.de

¹former VETO

Participating Institutes and Members

Max-Planck-Institute for Nuclear Physics, Heidelberg, Germany

C. BAUER, D. BAUMEISTER¹, W. HOFMANN, K.T. KNÖPFLE, S. LÖCHNER²
M. SCHMELLING, E. SEXAUER³

NIKHEF / Free University Amsterdam, The Netherlands

N. VAN BAKEL⁴, M. VAN BEUZEKOM, E. JANS, S. KLOUS, H. VERKOOIJEN

Physics Institute, University of Heidelberg, Heidelberg, Germany

M. FEUERSTACK-RAIBLE⁵, U. TRUNK⁶

University of Oxford, Oxford, United Kingdom

N. HARNEW, N. SMALE⁶

¹ now at Continental Teves AG, Frankfurt a. M., Germany

² now at Gesellschaft für Schwerionenforschung mbH, Darmstadt, Germany

³ now at Dialog Semiconductors, Kirchheim-Nabern, Germany

⁴ now at Stanford Linear Accelerator Center, Menlo Park, USA

⁵ now at Fujitsu Mikroelektronik GmbH, Dreieich-Buchsschlag, Germany

⁶ now at Max-Planck-Institute for Nuclear Physics, Heidelberg, Germany

Contents

1	Chip Architecture	7
2	Electrical Specifications	9
2.1	DC Characteristics	9
2.2	Signal Levels	9
2.3	Output Characteristics	10
3	Operating the <i>Beetle</i> Chip	12
3.1	Front-end Pulse Shape	12
3.2	Equivalent Noise Charge	13
3.3	Test Channel	14
3.4	Reset Modes	14
3.5	Readout Modes	15
3.6	Internal Test Pulses	15
3.7	Comparator Operation	17
3.7.1	Comparator Configuration	18
3.7.2	Threshold Adjustment	18
3.7.3	Comparator Masking	18
3.7.4	Comparator Channel Mapping	18
3.8	Timing Specifications	18
3.9	Diagnostic Signals	19
3.10	Daisy Chain	19
4	Slow Control	23
4.1	I ² C-Interface	23
4.2	Bias and Configuration Registers	24
4.3	Single Event Upset Robustness	25
5	How to get the <i>Beetle</i> Chip working	29
6	Known Problems and Limitations	31
A	Pad Description	32
A.1	Front Pads	34
A.2	Bottom Pads	37
A.3	Backside Pads	38
A.4	Top Pads	40
B	Optical Alignment Markers	42
C	Heidelberg Test Boards	43

List of Figures

1	Schematic block diagram of the <i>Beetle</i> readout chip	7
2	Current output driver levels	11
3	Example of a receiver circuit for the analogue and binary output signals	11
4	Semi-Gaussian pulse with the corresponding parameters	12
5	Variation of simulated front-end pulse shapes for different bias settings	13
6	Front-end pulse parameters for different settings	14
7	Test channel bias nodes	15
8	<i>Beetle</i> readout data formats	16
9	Test pulse triggering	17
10	Timing relation between <i>Reset</i> and <i>Trigger</i>	19
11	Timing relation between <i>Testpulse</i> and <i>Trigger</i>	19
12	Readout timing schemes	20
13	Non-consecutive and consecutive readout condition	20
14	Daisy chain composition	22
15	I ² C-bus write and read sequences for accessing registers on the <i>Beetle</i>	23
16	Mapping of shift register	27
17	Pad layout of <i>Beetle1.3</i> and <i>Beetle1.4</i>	32
18	Pad layout of <i>Beetle1.5</i>	33
19	Optical alignment markers	42
20	Pin configuration of the Heidelberg daughter board	43
21	Top layer of the Heidelberg daughter PCB (version 03/2003)	44
22	Bottom layer of the Heidelberg daughter PCB (version 03/2003)	45
23	Bonding diagram for <i>Beetle1.3</i> and <i>Beetle1.4</i> with comparator operation	46
24	Bonding diagram for <i>Beetle1.3</i> and <i>Beetle1.4</i> without comparator operation	47
25	Bonding diagram for <i>Beetle1.5</i> with comparator operation	48
26	Bonding diagram for <i>Beetle1.5</i> without comparator operation	49
27	Top side layout of the Heidelberg mother board	50
28	Bottom side layout of the Heidelberg mother board	51
29	Pin configuration of the Heidelberg mother board	52
30	Schematic diagram of the Heidelberg mother board	53

List of Tables

1	DC characteristics of <i>Beetle</i>	9
2	Typical power consumption	9
3	Specification of signal levels	10
4	Measured equivalent noise charge of <i>Beetle1.3</i>	13
5	Mapping of test pulse amplitudes to analogue channels	17
6	Correlation between V_{rc} and time constant τ	17
7	Mapping of analogue input channels to comparator output channels	19
8	Signals for monitoring or diagnostics purposes	21
9	Corresponding bias settings of I_{buf} and V_d	24
10	Corresponding bias settings of $I_{voltbuf}$ and I_{pipe}	25
11	Bit assignment of the configuration register <i>ROCtrl</i>	26
12	Bit assignment of the configuration register <i>CompCtrl</i>	26
13	Bit assignment of a read access to the comparator register <i>CompChTh</i>	27
14	Bias and configuration registers of <i>Beetle</i>	28

Document Edition History

This manual describes the three *Beetle* chip versions 1.3, 1.4 and 1.5.

For *Beetle* versions 1.0 and 1.1 please refer to the corresponding version of this manual (LHCb-note LHCb-2001-046), for *Beetle* version 1.2 to the corresponding manual (LHCb-note LHCb-2002-055).

Version	Date	Author	Description
1.0	11.03.2004	DB, SL	document created
1.1	04.04.2004	SL	updated missing measurement values
1.2	12.04.2004	SL	pulse-parameters
1.3	16.04.2004	SL	modified chap. 4.2, Rclk divider
1.4	03.05.2004	SL	new table 10 (<i>Ipipe</i> / <i>Ivltbuf</i>), modified standard settings table 14
1.5	16.06.2004	SL	add modifications for <i>Beetle1.4</i> and <i>Beetle1.5</i>
1.51	23.06.2004	SL	modified first page (new coordinates for N. Bakel)
1.52	06.10.2004	SL	modified chap. A.2 and chap. A.4 (corrected <i>Beetle</i> version numbers)
1.53	24.11.2004	SL	modified wrong link in history table
1.54	05.01.2005	SL	revised document
1.55	03.03.2005	SL	add remarks to power-up reset (3.4) and EnableEDC pad (4.3)
1.6	09.04.2005	SL	changed description of <i>Beetle</i> Revision Id., modified organisation and programming of shift registers, modified section 3.7, add default values for <i>ROCtrl</i> in table 11
1.61	19.05.2005	SL	revised document
1.62	09.07.2005	SL	revised table 14
1.63	10.07.2005	SL	fixed an error in table 1 (DC characteristics), additional comment to the programming of shift registers in chapter 5
1.64	15.07.2005	SL	add layout of mother board (fig. 27 and 28)
1.65	01.08.2005	SL	fixed wrong reference
1.66	23.09.2005	SL	minor modifications
1.67	15.11.2005	SL	minor modifications, changed VETO to PUS
1.68	23.11.2005	SL	modified comparator description (cf. section 3.7)
1.69	07.03.2006	SL	modified description of comparator low-pass filter (cf. section 3.7)
1.70	07.04.2006	SL	revised document
1.71	05.05.2006	SL	revised document
1.72	15.05.2006	SL	revised document
1.73	05.06.2006	SL	add <i>Beetle</i> chip version bug description (cf. section 6)
	22.08.2006	SL	document maintenance closed

Chip Version History

Version	Submission Date	Changes relating to previous version
<i>Beetle1.0</i>	April 2000	
<i>Beetle1.1</i>	March 2001	<p>extended test channel including pipeamp output, modified pipeline layout</p> <p>analogue delay element for I²C-SDA line added</p> <p>modified pipeamp, modified bias network of pipeamp</p> <p>modified multiplexer</p> <p>modified tristate buffer in control circuit</p>
<i>Beetle1.2</i>	April 2002	<p>implementation of a new front-end (set 2c of <i>BeetleFE1.1</i>)</p> <p>modified analogue input pad geometry (elongated pad opening)</p> <p>introduction of SEU robustness scheme</p> <p>restriction of readout time to 900 ns</p> <p>introduction of 8 additional status bits in data header</p> <p>introduction of a power-up reset</p> <p>introduction of comparator mask and test pulse selection bit per channel</p> <p>on-chip trigger synchronisation</p> <p>hard-wired I²C-chip address (defined via bond pads)</p> <p>introduction of SCHMITT-triggers in the I²C-pads</p> <p>reduced DAC resolution from 10 to 8 bits, increased max. bias current to 2 mA</p>
<i>Beetle1.3</i>	June 2003	<p>fix of sticky charge effect: analogue delay of MuxTrack signal</p> <p>increased comparator channel threshold resolution (5 bits)</p> <p>improved output buffer: fully diff. current buffer, increased gain</p> <p>bug fixes in control logic: daisy chain operation, reduced Rclk frequency</p> <p>new I²C-pads: 5 V compatible</p> <p>reduced number of flip-flops in multiplexer (from 414 to 138)</p> <p>reduced number of clock buffers in logic core (from 275 to 104)</p> <p>on-chip blocking of power nets (total blocking capacitance: $\mathcal{O}(1 \text{ nF})$)</p> <p>modified front-end power pad distribution</p> <p>improved shaper power routing, improved front-end biasing scheme</p> <p>separation of comparator core power from comparator LVDS power</p> <p>improved pipeamp power routing</p> <p>split power supply of multiplexer and logic core, improved multiplexer timing</p> <p>implementation of two new power pads for logic core</p> <p>merged pad openings of adjacent power pads</p> <p>improved guard-ring structures (n-well and substrate contacts)</p> <p>increased overall chip size by 300 μm in x: 5 400 \times 6 100 μm^2</p>
<i>Beetle1.4</i>	May 2004	<p>fixed parity bit of Pipeline Column Number (PCN)</p> <p>fixed even/odd crosstalk in pipeline</p> <p>new modified comparator</p> <p>changed <i>Beetle</i> revision number, add optical alignment markers</p>
<i>Beetle1.5</i>	May 2004	<p>split analogue power of front-end and comparator into two nets</p> <p>new pipeline cell</p> <p>new multiplexer timing (to reduce the header crosstalk)</p> <p>modified pipeamp, improved power routing</p> <p>changed <i>Beetle</i> revision number</p> <p>new test structure</p>

1 Chip Architecture

The *Beetle* can be operated as analogue or alternatively as binary pipelined readout chip. It implements the basic RD20 front-end electronics architecture [1, 2, 3]. Figure 1 shows a schematic block diagram of the chip.

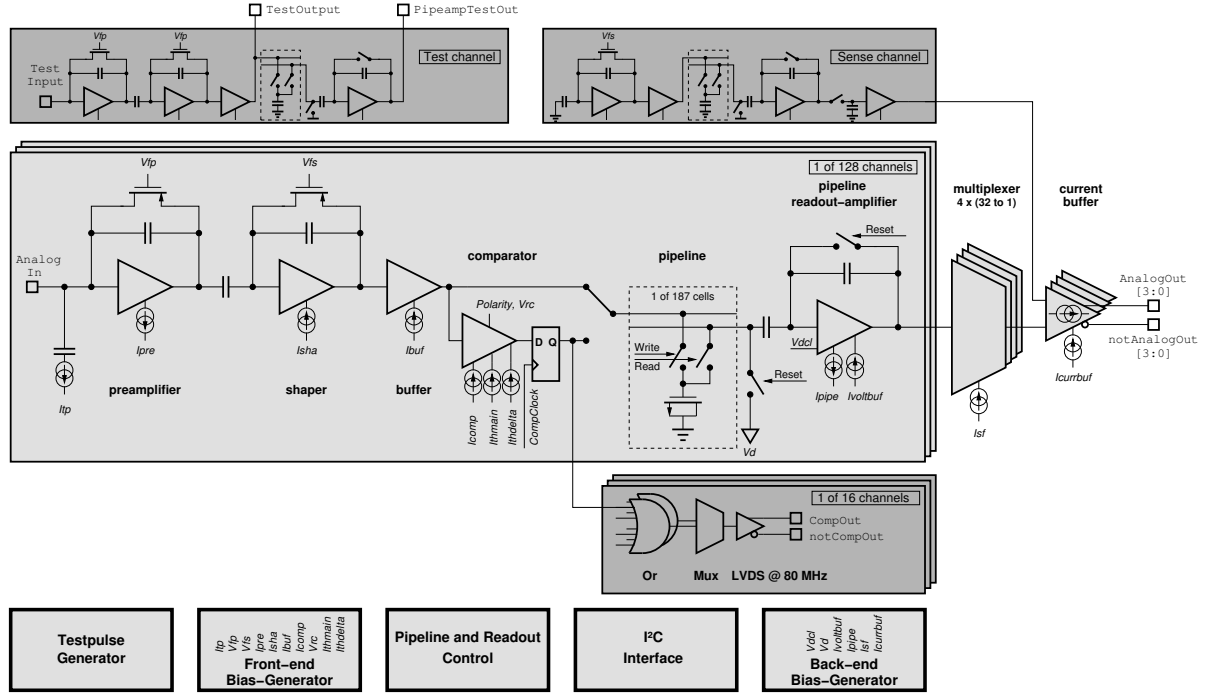


Figure 1: Schematic block diagram of the *Beetle* readout chip.

The chip integrates 128 channels, each consisting of a low-noise charge-sensitive preamplifier, an active CR-RC pulse shaper and a buffer. They form the analogue front-end. The equivalent noise charge (ENC) of the front-end has been measured as $ENC = 497 e^- + 48.3 e^- / pF \cdot C_{in}$. The shape of the front-end pulse can be chosen according to the specific requirements of the application. The minimum rise time (10-90%) is well below 25 ns, the remainder of the peak voltage after 25 ns can be adjusted to less than 30% for load capacitances $C_{in} \leq 35 pF$. A comparator discriminates the front-end's output pulse. The threshold is adjustable per channel and input signals of both polarities can be processed. Four adjacent comparator channels are grouped by a logic OR, latched, multiplexed by a factor of 2 and routed off the chip via low voltage differential signalling (LVDS) ports at 80 MHz. Either the shaper- or the comparator output is sampled with the LHC bunch-crossing frequency of 40 MHz into an analogue pipeline which has a programmable latency of max. 160 sampling intervals and an integrated multi-event buffer of 16 stages. The signal stored in the pipeline is transferred to the multiplexer via a resettable charge-sensitive amplifier (pipeamp). Within a readout time of 900 ns current drivers bring the serialised data off chip. The output of a dummy channel is subtracted from the analogue data to compensate common mode effects. All amplifier stages are biased by forced currents. On-chip digital-to-analogue converters (DACs) with 8 bit resolution generate the bias currents and voltages. For test and calibration purposes a charge injector with adjustable pulse height is implemented on each channel. The bias settings and various other parameters like the trigger latency can be controlled via a standard I²C-interface [6]. All digital control and data signals, except those for the I²C-ports, are routed via LVDS ports.

The choice of a deep-submicron process technology (0.25 μm standard CMOS) with a thin gate oxide ($t_{ox} \approx 62 \text{ \AA}$) and the consistent use of enclosed NMOS transistors reduces a shift in the transistor

threshold voltage and eliminates "end-around" leakage current paths. This establishes a total dose radiation hardness in excess of 130 Mrad. Single Event Latch-up (SEL) is suppressed by means of guard-rings. The continuous use of triple-redundant logic ensures a robustness against Single Event Upset (SEU).

2 Electrical Specifications

2.1 DC Characteristics

Table 1: DC characteristics of *Beetle*

Supply	Min. [V]	Nom. [V]	Max. [V]	Description
Vdda	2.3	2.5	2.7	Positive analogue supply (back-end)
Gnda	-0.2	0.0	0.2	Negative analogue supply (back-end)
Vddd	2.3	2.5	2.7	Positive digital supply
Gddd	-0.2	0.0	0.2	Negative digital supply
VddPre	2.3	2.5	2.7	Positive analogue preamplifier supply
GndPre	-0.2	0.0	0.2	Negative analogue preamplifier supply (detector ground)
VddaComp	2.3	2.5	2.7	Positive analogue comparator supply (<i>only Beetle1.5</i>)
GndaComp	-0.2	0.0	0.2	Negative analogue comparator supply (<i>only Beetle1.5</i>)
VdddComp	2.3	2.5	2.7	Positive digital comparator supply
GdddComp	-0.2	0.0	0.2	Negative digital comparator supply
VddCPB	2.3	2.5	2.7	Positive comparator pad supply at bottom side
GndCPB	-0.2	0.0	0.2	Negative comparator pad supply at bottom side
VddCPT	2.3	2.5	2.7	Positive comparator pad supply at top side
GndCPT	-0.2	0.0	0.2	Negative comparator pad supply at top side
VddMux	2.3	2.5	2.7	Positive multiplexer supply
GndMux	-0.2	0.0	0.2	Negative multiplexer supply
VddTX	2.3	2.5	2.7	Positive output driver supply
GndTX	-0.2	0.0	0.2	Negative output driver supply

Power Consumption Typical values for the power consumption of a *Beetle* chip are given in table 2 for various setup configurations. Nominal register settings refer to table 14.

Table 2: Typical power consumption.

Chip configuration					I _{supply} [mA]		P [mW/ch]	
Comparator		Clock	Trigger	Registers	analogue readout ports			
LVDS term.	digital	40 MHz	1.1 MHz		1	4	1	4
open	disabled	no	no	0	24.5	24.5	0.48	0.48
open	disabled	yes	no	0	64.5	64.5	1.26	1.26
open	disabled	yes	yes	0	64.5	64.5	1.26	1.26
open	disabled	no	no	nom.	192.0	221.5	3.75	4.33
open	disabled	yes	no	nom.	232.0	261.5	4.53	5.11
open	disabled	yes	yes	nom.	237.0	267.0	4.63	5.21

2.2 Signal Levels

The *Beetle* chip has 3 different kind of I/O pads. The signal levels for these pads are given in table 3.

Table 3: Specification of signal levels.

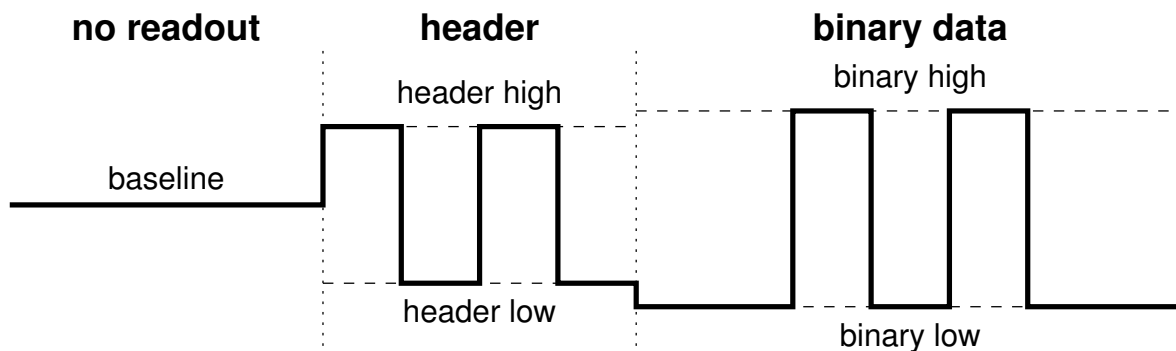
I ² C							
	logic 0			logic 1			Unit
	Min.	Max.	Typ.	Min.	Max.	Typ.	
input	-0.7	1.1	0.0	1.5	7.0	2.5	V
output	—	—	0.0	—	—	2.5	V
CMOS							
	logic 0			logic 1			Unit
	Min.	Max.	Typ.	Min.	Max.	Typ.	
input	-0.7	1.1	0.0	1.4	3.3	2.5	V
output	—	—	0.0	—	—	2.5	V
LVDS (100 Ω termination)							
	offset voltage			differential voltage			Unit
	Min.	Max.	Typ.	Min.	Max.	Typ.	
input	0.0	2.5	1.2	0.1	2.5	0.2	V
output	—	—	1.02	—	—	1.38	V

2.3 Output Characteristics

The *Beetle* chip provides an *analogue* as well as a *binary* output mode. A differential current is transmitted in each case by the *Beetle* current output driver.

Figure 2 specify the signal levels of the *Beetle* current output driver for different modes of operation. All levels were measured with a 100 Ω termination resistor between `AnalogOut<X>` and `notAnalogOut<X>`. The internal current of the output driver was programmed to the nominal value given in table 3.

Figure 3 gives an example of a receiver circuit for analogue signals using the AD8130 trans-impedance amplifier [4] and binary signals using the DS90C032 [5] LVDS receiver.



		BinaryHeader: ON CompDisable: OFF PipelineMode: ON			BinaryHeader: OFF CompDisable: OFF PipelineMode: ON			BinaryHeader: OFF CompDisable: ON PipelineMode: ON			BinaryHeader: OFF CompDisable: ON PipelineMode: OFF		
		V_{AO} [mV]	$V_{\overline{AO}}$ [mV]	I_{out} [mA]	V_{AO} [mV]	$V_{\overline{AO}}$ [mV]	I_{out} [mA]	V_{AO} [mV]	$V_{\overline{AO}}$ [mV]	I_{out} [mA]	V_{AO} [mV]	$V_{\overline{AO}}$ [mV]	I_{out} [mA]
baseline		1152	824	3.28	973	978	-0.05	973	978	-0.05	973	978	-0.05
header	high	840	1184	-3.44	916	1058	-1.42	916	1058	-1.42	916	1058	-1.42
	low	1152	824	3.28	1014	912	1.29	1014	912	1.29	1014	912	1.29
binary	high	760	1432	-6.72	760	1432	-6.72	1121	842	2.79	analogue readout		
	low	1164	816	3.48	1164	816	3.48						

Figure 2: Current output driver levels, measured over a $100\ \Omega$ resistor

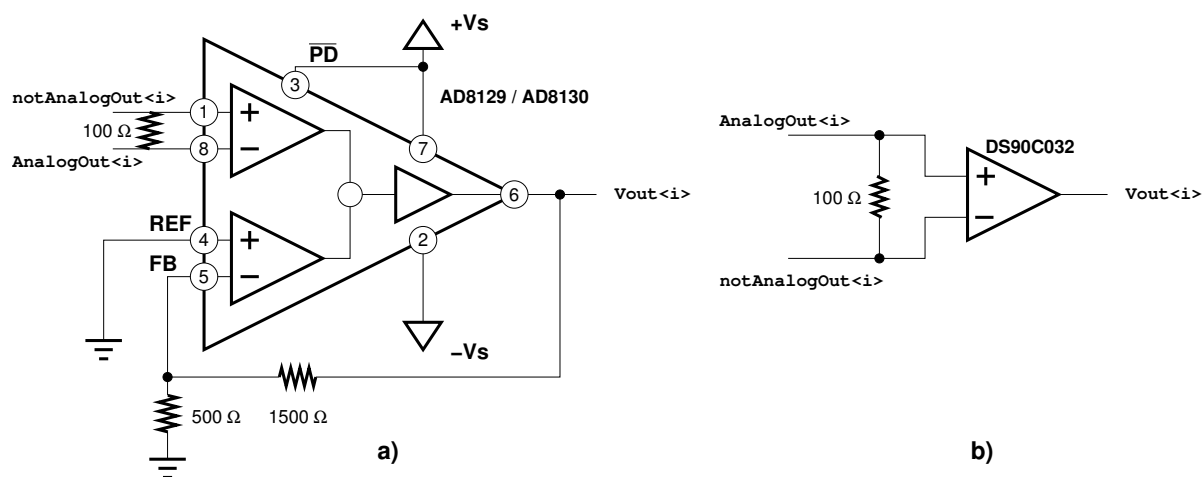


Figure 3: Example of a receiver circuit for the analogue (a) and binary (b) output signals. In case of analogue signals the AD8130 amplifier is used, in case of binary signals the DS90C032 LVDS receiver.

3 Operating the *Beetle* Chip

3.1 Front-end Pulse Shape

The front-end output signal is a semi-Gaussian pulse which can be characterised by three parameters:

- peaking time t_p (0 – 100%) or rise time t_r (10 – 90%),
- peaking voltage V_p and
- remainder R , which is the ratio between the signal voltage 25 ns after the peak (V_{25+}) and V_p .

The peaking time is sometimes hard to measure since the starting point of the pulse is not well defined, so the rise time t_r (10 – 90%) is usually quoted. Figure 4 explains the various parameters.

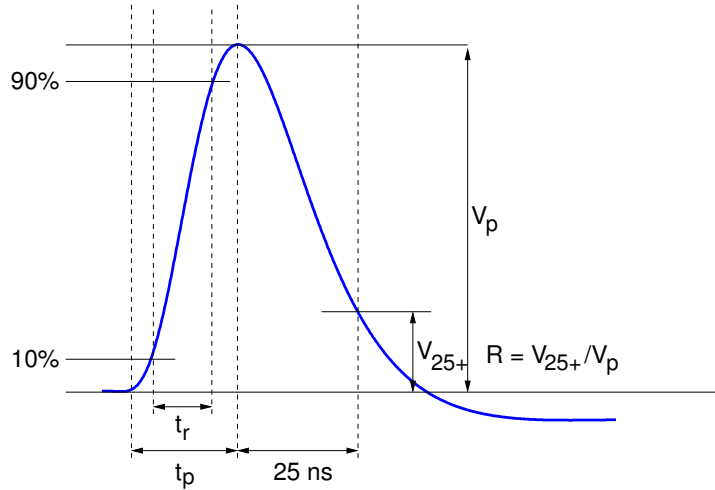


Figure 4: Semi-Gaussian pulse with the corresponding parameters characterising the shape.

Information about the front-end’s pulse shape can be obtained on a *Beetle* readout chip from either the test channel output (`TestOutput`, pad no. 242) or from a *pulse shape scan*. Here, the front-end’s output is read out via the pipelined path while the preamplifier input signal is shifted w.r.t. the sampling clock.

The pulse shape can be varied by 5 bias parameters:

Ipre sets the preamplifier bias current. Higher currents decrease the rise time and the remainder and increase the pulse undershoot.

Isha defines the shaper bias current. Increasing currents shift the DC-offset to lower values and result in a slightly decreasing rise time, remainder and undershoot.

Ibuf sets the buffer bias current. It does not affect the shape of the pulse, but the DC-offset.

Vfp determines the preamplifier feedback resistance. It defines the time constant for discharging the preamplifier’s integration capacitor and therefore the tolerable input charge rate.

Vfs controls the shaper feedback resistance. Increasing Vfs values enlarge the peaking time, the peaking voltage as well as the remainder (cf. figure 6).

Figure 5 depicts the variation of the pulse shape for four example bias parameter settings. For the nominal settings listed in table 14, i.e. $Ipre = 600 \mu A$, $Isha = Ibuf = 80 \mu A$, $Vfp = Vfs = 0 V$, the front-end sensitivity $A_Q = V_{FEout}/Q_{in} = 38 mV/22000 e^- = 38 mV/MIP$.

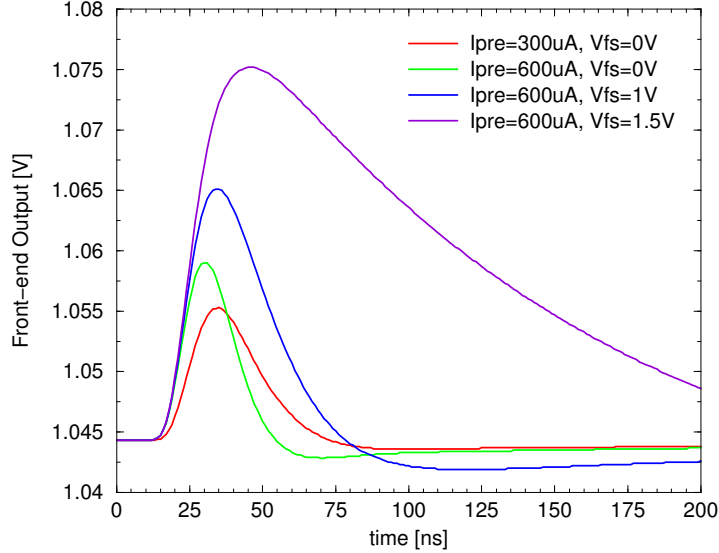


Figure 5: Variation of simulated front-end pulse shapes for settings ($I_{sha} = I_{buf} = 80 \mu\text{A}$, $V_{fp} = 0 \text{V}$).

The behaviour of the front-end pulse parameters is strongly coupled to the detector load capacitances. Figure 6 shows the variation of

- peaking time t_p (0 – 100%) [upper left plot],
- rise time t_r (10 – 90%) [upper right plot],
- peaking voltage V_p [lower left plot] and
- remainder R [lower right plot]

for different detector capacitances and for four different shaper feedback settings V_{fs} .

3.2 Equivalent Noise Charge

The equivalent noise charge (ENC) of a complete *Beetle1.3* readout chip has been measured for different front-end settings. ENC values are given in table 4 for different shaper feedback settings V_{fs} . Nominal register settings refer to table 14. For *Beetle1.4* and *Beetle1.5* one expects roughly the same results, because all three chip versions have the same front-end.

Table 4: Measured equivalent noise charge of *Beetle1.3* for different shaper feedback settings V_{fs} .

V_{fs} [mV]	Equivalent noise charge
0	$\text{ENC} = 547.7 e^- + 52.64 e^- / \text{pF} \cdot C_{in}$
100	$\text{ENC} = 539.1 e^- + 51.89 e^- / \text{pF} \cdot C_{in}$
400	$\text{ENC} = 542.8 e^- + 49.38 e^- / \text{pF} \cdot C_{in}$
1000	$\text{ENC} = 465.1 e^- + 45.22 e^- / \text{pF} \cdot C_{in}$

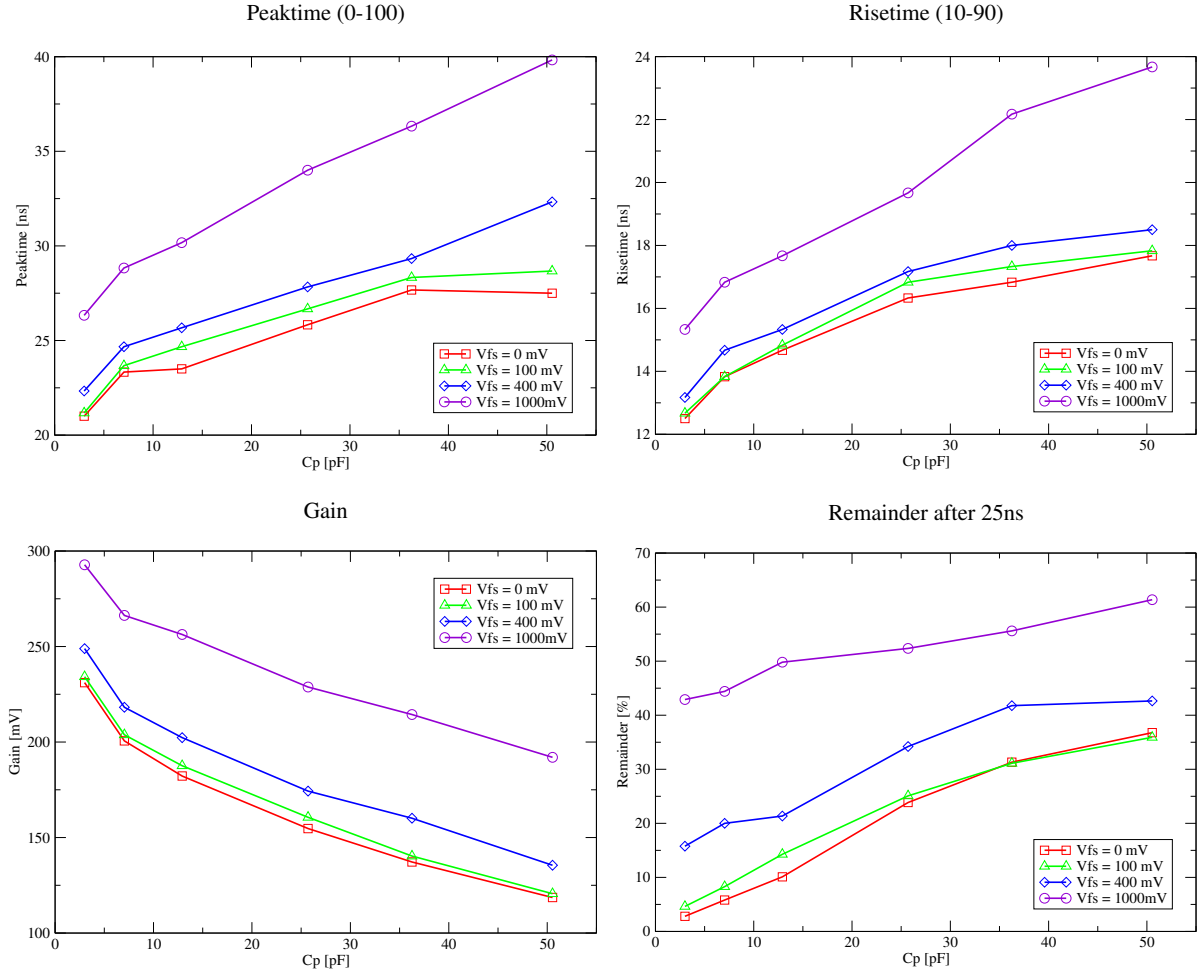


Figure 6: Front-end pulse parameters for different shaper settings V_{fs} and different detector load capacitances C_p

3.3 Test Channel

The *Beetle* chip integrates beside the 128 channels a *test channel* with direct access to the front-end output (**TestOutput**, pad no. 242 on *Beetle1.3* and *1.4* resp. pad no. 243 on *Beetle1.5*) as well as the pipeamp output (**PipeampTestOut**, pad no. 218 (*1.3* and *1.4*) resp. 217 (*1.5*)). An input charge can be injected either via the **TestInput** port (pad no. 6) or via the internal test pulse generator (+1 step, cf. 3.6). Additionally, 5 internal voltage nodes of the test channel's front-end are accessible on test pads: **Prebias**, **Prebias1**, **Shabias**, **Shabias1** and **Bufbias**. Figure 7 illustrates the various bias nodes, which are common for all *Beetle* front-ends.

3.4 Reset Modes

Two different types of reset exist on *Beetle*.

- *Power-up reset* is activated immediately when the power of the chip is switched on. The reset's time-constant, i.e. the time between "power-on" and the reset becoming inactive, can be adjusted via an external capacitance connected to the **PowerupReset** pad no. 192. For typical capacitance values like $C_{ext} = 10$ nF (100 nF), the time constant τ results in $\tau = 28$ ms (280 ms). All *Beetle*

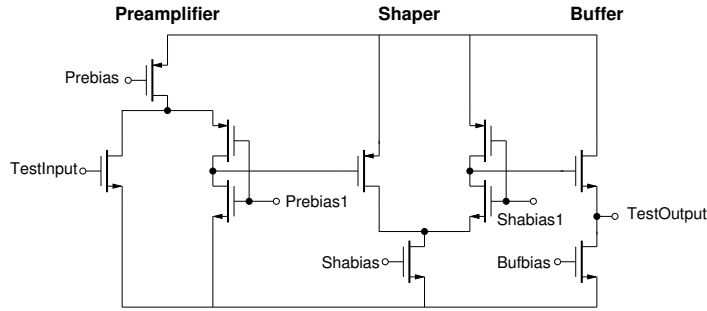


Figure 7: Test channel bias nodes.

registers are reset to 0 and the I²C-interface is initialised.

Manual access to the power-up reset control is also possible via the `PowerupReset` pad. The reset is enabled by switching this pad to Gnd and accordingly set the chip back to operation mode by connecting the pad to Vdd².

- *External reset* is controlled by the `Reset` port (see section A.3). It resets the pipeline write and trigger pointer to column number 0 and initialises the control logic's state machines. The rising edge of `Reset` re-initialises also the I²C-interface. The minimum reset width is 25 ns, i.e. one sampling clock cycle.

3.5 Readout Modes

The readout of the *Beetle* chip is synchronous to the readout clock *Rclk*, which is generated on-chip from the sampling clock *Sclk* (`Clk` port). For operation at LHC, sampling and readout clock have the same frequency. For other applications, the readout clock frequency can be reduced to a fraction of *Sclk* (cf. 4.2).

The *Beetle* readout chip provides three different readout modes³:

Analogue readout on 4 ports Each port carries 4 header bits plus 32 channels. Data transmission is synchronous to the rising edge of the readout clock and takes 900 ns per trigger.

Binary readout on 2 ports Each port carries 8 header bits plus 64 channels. Data transmission is synchronous to both edges of *Rclk*. The readout takes 900 ns per trigger.

Analogue readout on 1 port This is for applications with less demanding readout speed requirements. The readout lasts 3.6 μ s per trigger.

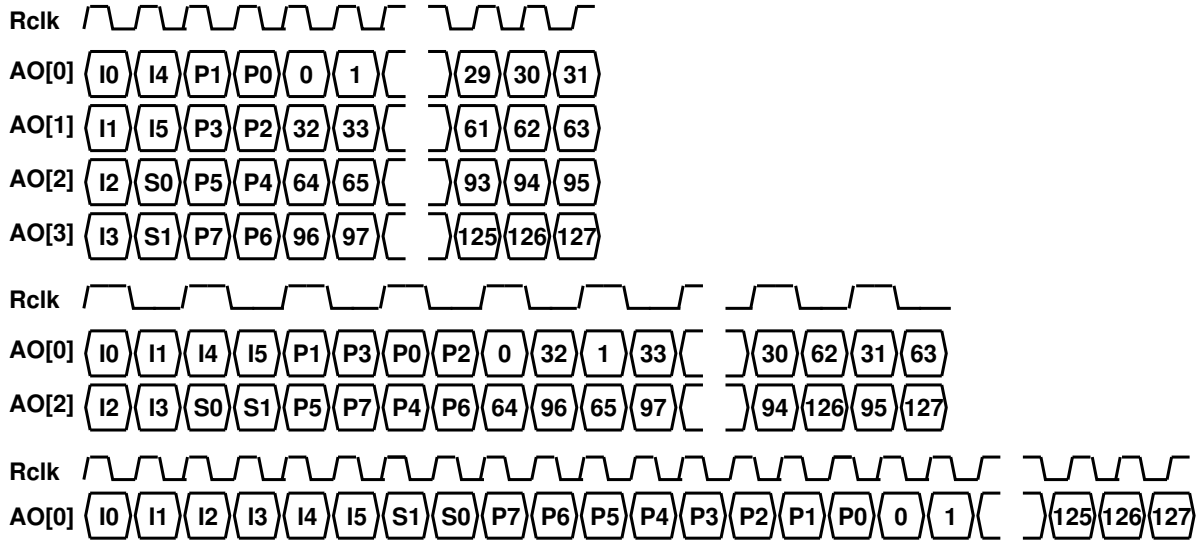
Figure 8 shows the assignment of the header bits and analogue input channels to the output channels in the different modes. The meaning of the various header bits is described beneath the assignment.

3.6 Internal Test Pulses

Test pulses can be injected into the preamplifier with an on-chip generator. A step like pattern corresponding to +1 and -1 times a reference signal amplitude is coupled to the 129 channels (table 5). Its amplitude alternates with the channel number and can be adjusted with the *Itp* bias register (cf. table 14). A test pulse is triggered via the rising edge of `Testpulse` signal (pad no. 177, 178) and can be enabled per channel by the *TpSelect* register (cf. 4.2). Figure 9 shows the correlation between the `Testpulse` port and the internal test pulse trigger. The test pulse is independent from `Clk`.

²reset enable: signal level of `PowerupReset` < 0.410 V; reset disable: signal level > 1.950 V

³The specification of the readout time assumes *Rclk* = *Sclk* = 40 MHz.



From top to bottom: Analogue readout mode: 32 analogue channels are multiplexed onto 4 ports with up to 40 MHz. Binary readout mode: 64 binary channels are multiplexed onto 2 ports with up to 80 MHz. Readout mode for less demanding readout speed requirements: 128 analogue channels are multiplexed onto 1 port with up to 40 MHz.

Bit		Description
I0	LeadingBit	always active (= 1)
I2	ActiveEDC	1 indicates active error detection and correction (EDC) logic
I3	ParCompChTh	(even) parity of register <i>CompChTh</i> (reg. no. 20, cf. table 14)
I4	ParCompMask	(even) parity of register <i>CompMask</i> (reg. no. 21, cf. table 14)
S0		LSB of register <i>SEUcounter</i> (reg. no. 23, cf. table 14)
S1		bit 1 of register <i>SEUcounter</i> (reg. no. 23, cf. table 14)
P0		LSB of pipeline column number
P1		bit 1 of pipeline column number
P2		bit 2 of pipeline column number
P3		bit 3 of pipeline column number
P4		bit 4 of pipeline column number
P5		bit 5 of pipeline column number
P6		bit 6 of pipeline column number
P7		MSB of pipeline column number
special for <i>Beetle1.3</i> :		
I1	ParPCN	(even) parity of pipeline column number (PCN)
I5	ParTpSelect	(even) parity of register <i>TpSelect</i> (reg. no. 22, cf. table 14)
special for <i>Beetle1.4</i> and <i>Beetle1.5</i> :		
I1	ParTpSelect	(even) parity of register <i>TpSelect</i> (reg. no. 22, cf. table 14)
I5	ParPCN	(even) parity of pipeline column number (PCN)

Figure 8: *Beetle* readout data formats and definition of the header bits. I1 and I5 are swapped between *Beetle1.3* and *Beetle1.4* / *1.5*.

Table 5: Mapping of test pulse amplitudes to analogue channels.

Channel no.	Test channel	0	1	2	3	...	124	125	126	127
Test pulse step height	∓ 1	± 1	∓ 1	± 1	∓ 1	...	± 1	∓ 1	± 1	∓ 1

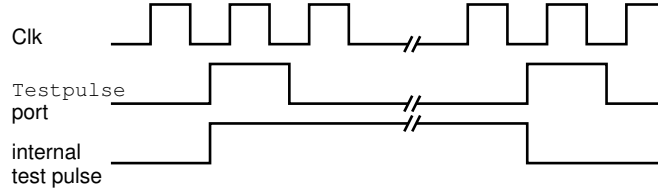


Figure 9: Test pulse triggering.

Calibration The relation between I_{tp} and the injected charge Q_{in} is given:

- $Q_{in} = 131.2 e^- / \mu A \cdot I_{tp}$

or

- $Q_{in} = 1025 e^- / [\text{regbit}] \cdot I_{tp} [\text{regbit}]$

3.7 Comparator Operation

The comparator circuit consists of an integrator, a threshold generator and a discriminator. The integrator tracks the DC-offset of the shaped pulse with a variable time constant τ between $16 \mu s$ and $10 ms$, which can be adjusted via the Vrc register (cf. table 14). The programmable range of Vrc is between 0 and $1.25 V$, but only values up to $330 mV$ will have an influence to the time constant of the low-pass filter. A more detailed view of the correlation between Vrc and τ is shown in table 6. The DC-offset vary from channel to channel and is added to the threshold voltage. The threshold level is adjustable with a resolution of 5 bits per channel. With the rising edge of the comparator's own `CompClock` (pad no. 146, 147) the discriminator output is sampled.

Table 6: Correlation between Vrc and the time constant τ of the comparator low-pass filter.

Vrc	τ	Vrc	τ
0 mV	16.3 μs	200 mV	375.8 μs
20 mV	18.0 μs	220 mV	558.1 μs
40 mV	24.7 μs	240 mV	920.8 μs
60 mV	31.6 μs	280 mV	1.4 ms
80 mV	41.6 μs	300 mV	4.6 ms
100 mV	56.3 μs	320 mV	9.2 ms
120 mV	78.7 μs	340 mV	>10.0 ms
140 mV	112.3 μs		
160 mV	164.4 μs		
180 mV	245.5 μs		

3.7.1 Comparator Configuration

The comparator is configured via the register *CompControl* (see table 12 and table 14). *PipelineMode* defines the mode of operation of the comparator. *PipelineMode* = 0 selects the analogue mode, in which the output of the front-end amplifier is transferred to the pipeline. In binary mode (*PipelineMode* = 1) the comparator output is fed into the pipeline. *CompDisable* = 1 turns off the comparator's bias current. *CompPolarity* selects between an inverting (0) or non-inverting (1) comparator operation. *CompMode* switches between two different kinds of output signal. With *CompMode* = 0 the output is active as long as the comparator input signal is above the threshold level. With *CompMode* = 1 the output is only active for one *CompClock* cycle, independent from the time the input signal is above the threshold.

3.7.2 Threshold Adjustment

The threshold level is generated from two programmable currents. *Ithmain* (register address 8) determines the global threshold, which is common to all channels. *Ithdelta* (register address 7) defines an additional delta threshold.

The comparator threshold register (*CompChTh*, address 20) selects the number of delta thresholds which are being subtracted from the global threshold. This register is operated as a shift register. The bits *CompChTh*[4:0] are being assigned to channel *k*. To define the delta threshold of all channels, the *CompChTh* register has to be programmed 128 times consecutively. A shift mechanism provides the bits to the channels in the order Ch[0], Ch[1], Ch[2], ..., Ch[126], Ch[127].

3.7.3 Comparator Masking

The comparator mask register (*CompMask*, address 21) deactivates the operation of a single comparator channel. Eight adjacent channel mask bits are combined to one group and can be programmed via the shift register *CompMask*.

A detailed description of the mapping and programming of the shift register is explained in chapter 4 and especially in fig. 16.

3.7.4 Comparator Channel Mapping

The comparator outputs are LVDS drivers. Each driver sends data of two combined comparator groups, the first group of ORed channels during the high phase of *CompClock*, the second during the low phase. The mapping of the channels to the comparator outputs is shown in table 7.

3.8 Timing Specifications

Reset, Trigger, Testpulse The timing relation between *Reset* and *Trigger* in order to trigger on pipeline column number *n* can be depicted from fig. 10, whereas $n = k$ modulo 187. *k* must be equal or greater than 1, *Latency* refers to the content of the Latency register (no. 16). **The external *Reset* and *Trigger* signals are sampled internally to the negative edge of *Clk*.**

Figure 11 depicts the timing relation between *Testpulse* and *Trigger*. *Latency* refers again to the content of the Latency register.

Readout Timing The *Beetle* chip has two different possible readout timings called *non-consecutive* and *consecutive* readout. A non-consecutive readout starts after a trigger occurs during a non-readout. If the *Beetle* receives a second trigger before a last readout is completed, the next readout is send as a consecutive readout. Figure 13 depicts the timing condition where the next readout starts as a consecutive readout (upper scheme) respectively the first condition where the next readout starts as a non-consecutive readout (lower scheme).

Figure 12 describe the readout timing of *Trigger*, *DataValid* and *AnalogOut* of the analogue readout mode on 4 ports. The upper plot shows a single readout burst (non-consecutive readout), the lower the case of a consecutive readout.

Table 7: Mapping of analogue input channels to comparator output channels.

Output port	High phase of CompClock	Low phase of CompClock
CompOut[15]	Ch[127]∨Ch[126]∨Ch[125]∨Ch[124]	Ch[123]∨Ch[122]∨Ch[121]∨Ch[120]
CompOut[14]	Ch[119]∨Ch[118]∨Ch[117]∨Ch[116]	Ch[115]∨Ch[114]∨Ch[113]∨Ch[112]
CompOut[13]	Ch[111]∨Ch[110]∨Ch[109]∨Ch[108]	Ch[107]∨Ch[106]∨Ch[105]∨Ch[104]
CompOut[12]	Ch[103]∨Ch[102]∨Ch[101]∨Ch[100]	Ch[99]∨Ch[98]∨Ch[97]∨Ch[96]
CompOut[11]	Ch[95]∨Ch[94]∨Ch[93]∨Ch[92]	Ch[91]∨Ch[90]∨Ch[89]∨Ch[88]
CompOut[10]	Ch[87]∨Ch[86]∨Ch[85]∨Ch[84]	Ch[83]∨Ch[82]∨Ch[81]∨Ch[80]
CompOut[9]	Ch[79]∨Ch[78]∨Ch[77]∨Ch[76]	Ch[75]∨Ch[74]∨Ch[73]∨Ch[72]
CompOut[8]	Ch[71]∨Ch[70]∨Ch[69]∨Ch[68]	Ch[67]∨Ch[66]∨Ch[65]∨Ch[64]
CompOut[7]	Ch[63]∨Ch[62]∨Ch[61]∨Ch[60]	Ch[59]∨Ch[58]∨Ch[57]∨Ch[56]
CompOut[6]	Ch[55]∨Ch[54]∨Ch[53]∨Ch[52]	Ch[51]∨Ch[50]∨Ch[49]∨Ch[48]
CompOut[5]	Ch[47]∨Ch[46]∨Ch[45]∨Ch[44]	Ch[43]∨Ch[42]∨Ch[41]∨Ch[40]
CompOut[4]	Ch[39]∨Ch[38]∨Ch[37]∨Ch[36]	Ch[35]∨Ch[34]∨Ch[33]∨Ch[32]
CompOut[3]	Ch[31]∨Ch[30]∨Ch[29]∨Ch[28]	Ch[27]∨Ch[26]∨Ch[25]∨Ch[24]
CompOut[2]	Ch[23]∨Ch[22]∨Ch[21]∨Ch[20]	Ch[19]∨Ch[18]∨Ch[17]∨Ch[16]
CompOut[1]	Ch[15]∨Ch[14]∨Ch[13]∨Ch[12]	Ch[11]∨Ch[10]∨Ch[9]∨Ch[8]
CompOut[0]	Ch[7]∨Ch[6]∨Ch[5]∨Ch[4]	Ch[3]∨Ch[2]∨Ch[1]∨Ch[0]

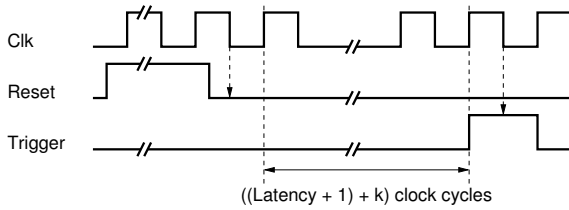


Figure 10: Timing relation between *Reset* and *Trigger* in order to trigger on a defined pipeline column number.

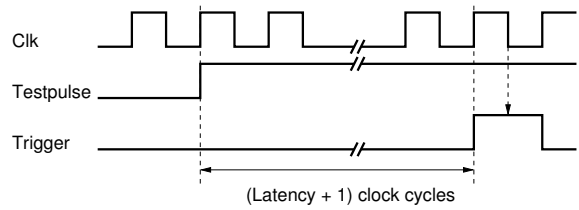


Figure 11: Timing relation between *Testpulse* and *Trigger*. *Latency* refers to the content of the latency register.

3.9 Diagnostic Signals

The *Beetle* chip provides several signals for monitoring or diagnostics purposes which are explained briefly in table 8.

WriteMon and *TrigMon* allow to check the physical latency of the chip. They are pulses with a width of one sampling clock cycle and a period of 187 cycles in case of an empty pipeline. Their relative distance is $(Latency + 1)$ clock cycles. *WriteMon* and

PPTout is the output of an internal test structure on *Beetle1.5* that is switched on/off via the pad *PPTenable* (pad no. 219). If *PPTenable* is not connected, the default setting is off. The output oscillates with a certain frequency that depends on the temperature and the process parameters of the chip. To activate *PPTout* the power pads *VddCPT* (pad no. 221) and *GndCPT* (pad no. 220) have also to be bonded.

3.10 Daisy Chain

The daisy chain allows several chips to share one, two or four output lines. It consists of two signal paths, a *token* and a *return token* path. They are built up by connecting the *RoTokenOut* (*RoReTokenIn*) pad of one chip with the *RoTokenIn* (*RoReTokenOut*) of the neighbouring chip (see fig. 14). The chip position in the chain has to be configured in the *ROCtrl* register (bits 3 and 4). A chip can be the first

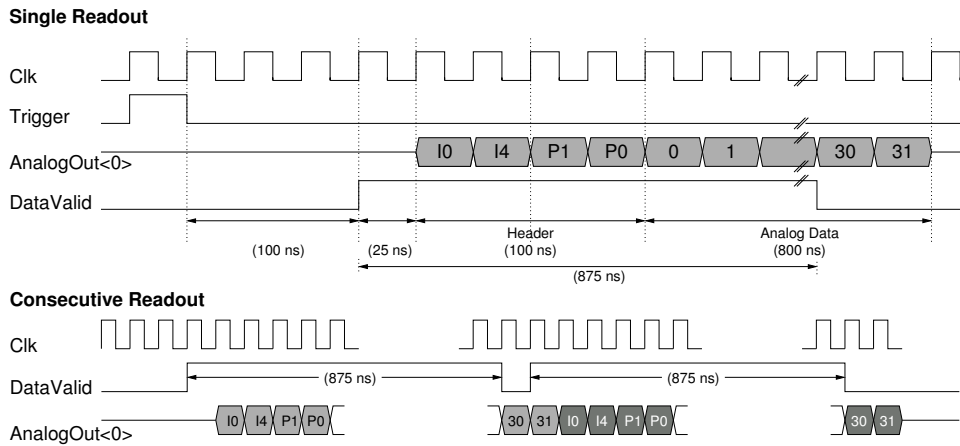


Figure 12: Readout timing schemes of the analogue readout mode on 4 ports. Only channel 0 is depicted. The upper plot shows a single readout burst, the lower the case of consecutive readout.

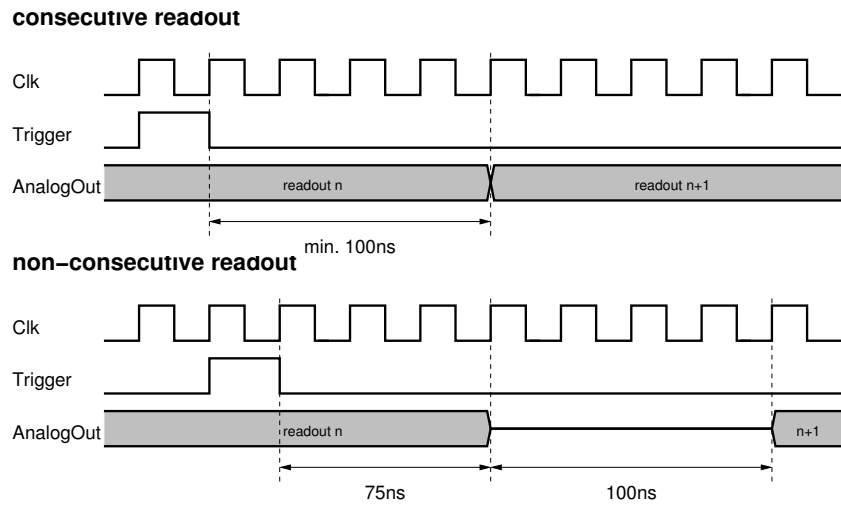


Figure 13: Non-consecutive and consecutive readout condition. The upper timing plot shows the last possible timing condition of a trigger where the next readout starts as a consecutive readout. The lower plot shows the first condition where the next readout starts as a non-consecutive readout.

Table 8: Signals for monitoring or diagnostics purposes. First column shows the signal name. The pad no. for chip version *1.3* and *1.4* are quoted in the second column, resp. for *1.5* in the third column. The last column describes briefly the function of the signal.

Signal name	Pad no. 1.3 / 1.4	Pad. no. 1.5	Description
Digital signals (all signals are active-high):			
FifoFull	166	166	indicates full derandomising trigger buffer; with 15 occupied FIFO entries, the next trigger activates FifoFull
TrigMon	171	171	indicates if pipeline trigger pointer passes column no. 0
WriteMon	172	172	indicates if pipeline write pointer passes column no. 0
DataValid	181, 182	181, 182	indicates presence of valid data on the AnalogOut ports; see fig. 12 for timing specifications
PPTout	—	218	output of internal test structure, that shifts with different temperature and/or different process parameter settings
Analogue signals:			
ProbeIDAC	139	—	internal current of front-end current DAC Ibuf
ProbeVrefBE	216	215	reference voltage of the internal back-end current source
ProbeIoutBE	217	216	control current to measure the internal back-end current source
PipeampTestOut	218	217	test channel output after pipeline-amplifier
TestOutput	242	243	front-end output of test channel (cf. 3.6)
Bufbias	243	244	internal bias node of front-end (cf. 3.6)
Shabias1	244	245	internal bias node of front-end (cf. 3.6)
Shabias	245	246	internal bias node of front-end (cf. 3.6)
Prebias1	246	247	internal bias node of front-end (cf. 3.6)
Prebias	247	248	internal bias node of front-end (cf. 3.6)

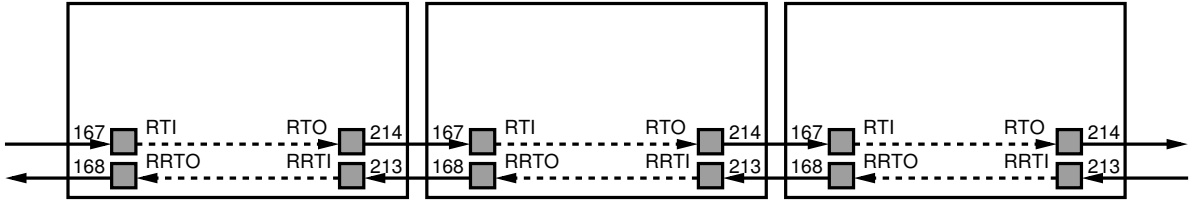


Figure 14: Daisy chain composition. The figures indicate the pad reference numbers (RTI = RoTokenIn, RRTO = RoReTokenOut, RTO = RoTokenOut, RRTI = RoReTokenIn).

(DaisyFirst = 1), an intermediate or the last (DaisyLast = 1) in the daisy chain.

In case of single chip operation, DaisyFirst and DaisyLast have to be set to 1. As well the bonding of the token pads can be skipped in this mode.

4 Slow Control

4.1 I²C-Interface

The chip's slow control interface is a standard mode I²C-slave device featuring a transfer rate of 100 kbit/s. The chip address, necessary to access a single device via the I²C-bus, is 7 bits wide and assigned via the address pads I2CAddr[6:0] (cf. section A.3). The *Beetle* chip responds to addresses in the range 8 – 119. The addresses 0000XXX and 1111XXX are reserved in the I²C-standard for other purposes [6].

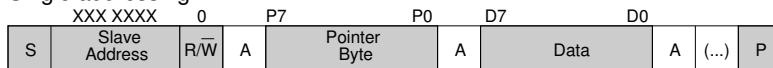
The internal registers are being accessed via a *pointer register*. It contains the address of the register to be written or read first. The pointer is internally incremented by 1 after each transferred data frame. In this way registers with adjacent addresses can be accessed consecutively. The pointer register itself remains unchanged, i.e. a new transfer will start at the original pointer position. Figure 15 explains the transfer sequences in write and read mode. Data is always transferred with the most significant bit (MSB) first. In write mode the chip address is transmitted after initialising the transfer, followed by the pointer byte and the data. After the transmission of one data frame, the pointer addresses the subsequent register because of its auto-incrementing function. The registers with addresses 20 – 23 are excepted. Registers 20 – 22 are implemented as 128-bit shift-registers (cf. 4.2), register 23 is the output of the SEU counter. A write access to this register resets it to 0. Hence, the auto-incrementing of the address pointer is only performed for addresses ≤ 19 . To access the addresses 20 – 23 the corresponding register has to be addressed directly.

The transfer of the pointer byte is obligatory in write mode. In read mode there are two versions:

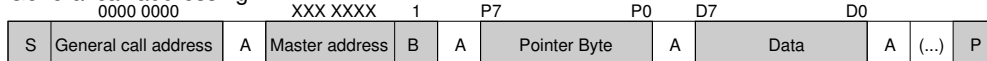
- **Preset pointer**
After initialising the transfer and sending the chip address data is immediately read out. The pointer has been set in a previous transfer.
- **Pointer set followed by immediate read-out**
After initialising the transfer and sending the chip address the pointer byte is transferred. The I²C-bus is re-initialised, the chip address is sent and data is read out.

Write mode

Single addressing

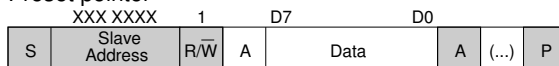


General call addressing



Read mode

Preset pointer



Pointer set followed by immediate readout

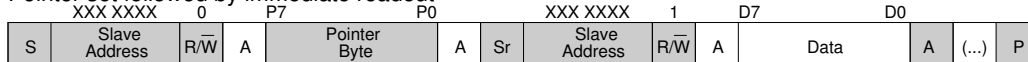


Figure 15: I²C-bus write and read sequences for accessing registers on the *Beetle*.

Commercially available I²C-devices usually operate at 3.3 V or 5 V. With version 1.3 or higher, such external devices can be directly connected to the *Beetle* I²C-interface.

4.2 Bias and Configuration Registers

Beetle contains 24 8-bit registers with the addresses 0 – 23. Table 14 lists all registers with physical range, resolution and nominal setting. Registers 0 – 15 are bias registers for the analogue stages.

Pipeamp reset potential: V_d Register 11 determines the potential to which the pipeamp is reset. This voltage should correspond to the DC output level of the front-end and is therefore depending on *Isha* and *Ibuf* (cf. 3.1). Table 9 gives typical values of V_d for $Isha = 80 \mu\text{A}$ and various *Ibuf* settings.

Table 9: Corresponding bias settings of *Ibuf* and V_d for $Isha = 80 \mu\text{A}$.

<i>Ibuf</i>		V_d	
Value	Reg. content	Value	Reg. content
39 μA	0x05	1.314 mV	0x86
47 μA	0x06	1.304 mV	0x85
55 μA	0x07	1.294 mV	0x84
63 μA	0x08	1.284 mV	0x83
71 μA	0x09	1.284 mV	0x83
78 μA	0x0A	1.275 mV	0x82
86 μA	0x0B	1.275 mV	0x82
94 μA	0x0C	1.275 mV	0x82
102 μA	0x0D	1.265 mV	0x81
110 μA	0x0E	1.265 mV	0x81
118 μA	0x0F	1.265 mV	0x81
125 μA	0x10	1.255 mV	0x80
251 μA	0x20	1.216 mV	0x7C

Pipeamp reference potential: V_{dcl} Register 12 adjusts the potential of the non-inverting input of the pipeamp.

Pipeamp bias currents: I_{pipe} and $I_{voltbuf}$ Register 10 (*Ipipe*) adjusts the bias of the pipeamp, whereas register 13 (*Ivoltbuf*) controls the bias of the V_{dcl} -buffer. Both bias nodes depend strongly on each other. Table 10 gives typical values of *Ivoltbuf* for various *Ipipe* settings.

Latency Register 16 defines the latency which has to be ≥ 10 and ≤ 160 for reliable chip operation.

↪ A change of the latency register is only made effective by applying a reset.

Rclk divider: $RclkDiv$ Register 18 defines the ratio between the readout clock Rclk and the sampling clock Sclk. The ratio ν_{Rclk}/ν_{Sclk} is defined as

$$\frac{\nu_{Rclk}}{\nu_{Sclk}} = \begin{cases} 1 & \text{for } RclkDiv = 0 \\ \frac{1}{2^{RclkDiv}} & \text{for } RclkDiv > 0 \end{cases}$$

and allows Rclk frequencies from 40 MHz down to ≈ 78 kHz. $RclkDiv = 0$ means, that Sclk and Rclk have the same frequency.

↪ A change of the *RclkDiv* register requires a following reset for proper chip operation.

Table 10: Corresponding bias settings of *Ivltbuf* and *Ipipe*

<i>Ipipe</i>		<i>Ivltbuf</i>	
Value	Reg. content	Value	Reg. content
78 μ A	0x0A	149 μ A	0x13
86 μ A	0x0B	149 μ A	0x13
94 μ A	0x0C	149 μ A	0x13
102 μ A	0x0D	157 μ A	0x14
110 μ A	0x0E	157 μ A	0x14
118 μ A	0x0F	157 μ A	0x14
125 μ A	0x10	165 μ A	0x15
133 μ A	0x11	173 μ A	0x16
141 μ A	0x12	180 μ A	0x17
149 μ A	0x13	180 μ A	0x17
157 μ A	0x14	188 μ A	0x18
165 μ A	0x15	196 μ A	0x19
173 μ A	0x16	196 μ A	0x19
180 μ A	0x17	204 μ A	0x1A
188 μ A	0x18	212 μ A	0x1B
196 μ A	0x19	212 μ A	0x1B
204 μ A	0x1A	220 μ A	0x1C

Mode of operation: *ROCtrl*, *CompCtrl* The registers 17 and 19 select the chip’s mode of operation (readout mode, daisy chain configuration) and define the comparator configuration. Tables 11 and 12 show the detailed bit assignment of the registers *ROControl* and *CompControl*. Note, that the three *ModeSelect* bits (*BinRO2*, *AnaRO1* and *AnaRO4*) are exclusive, i.e. only one bit is allowed to be set.

↪ A change of the *ROCtrl* register bit 4 – 0 requires a following reset for proper chip operation.

Shift registers Registers 20 – 22 (*CompChTh*, *CompMask*, *TpSelect*) are operated as shift-registers: *CompMask* and *TpSelect* form a 128-bit register each, segmented in 16 8-bit registers, *CompChTh* establishes a 1024 (= 128 × 8) bit register, whereas only 5 of the 8 bits per frame are assigned (cf. section 3.7.2). A consecutive write access to the corresponding register address shifts the data in 8-bit frames starting from the largest channel number (see fig. 16).

An unusual feature is the programming of the internal test pulse mask bit of the test channel. With a 17th consecutive write access to the *TpSelect* register, the value of *TpSelect* channel 7 is shifted into *TpSelect* of the test channel.

A read access to one of the shift registers returns the bits corresponding to channels 7 – 0 in case of *CompMask* and *TpSelect* and channel 0 in case of *CompChTh*. This allows a verification of the shifted data. In addition the unused bits (7 to 5) of *CompChTh* are used for reading back the *Beetle* chip version number (*RevId*). An overview of the register as well as the possible values for *RevId* are given in table 13.

SEU counter Register 23 is the output of the SEU counter (cf. 4.3). A write access to this register resets the content to 0. Note, that the two LSBs of the register *SEUcounts* are transmitted in the header (S[1:0]) of the analogue output stream (cf. 3.5).

4.3 Single Event Upset Robustness

Beetle continuously uses triple-redundant logic in order to assure the robustness against Single Event Upset (SEU), i.e. the change of the state of a memory device induced by ionisation. A logic bit is

Table 11: Bit assignment of the configuration register *ROCtrl*.

Bit	Function	Description	Nominal
0	BinRO2	binary readout on 2 ports	0
1	AnaRO1	analogue readout on 1 port	0
2	AnaRO4	analogue readout on 4 ports	1
3	DaisyFirst	first chip in daisy chain	1
4	DaisyLast	last chip in daisy chain	1
5	BinaryHeader	readout header levels of current driver	0
6	<i>not used</i>	—	0
7	ProbeEnable	enables probe pads ProbeVrefBE (pad no. 216)	0

*All switches are active-high. 1 enables the switch, 0 disables it.
Nominal settings are defined for LHCb readout mode*

Table 12: Bit assignment of the configuration register *CompCtrl*.

Bit	Function	Description
0	DisableCompLVDS	0: enable comparator LVDS output ports 1: disable comparator LVDS output ports
1	CompPolarity	0: inverting 1: non-inverting
2	PipelineMode	0: analogue readout 1: binary readout
3	CompDisable	0: enable comparator 1: disable comparator
4	CompMode	0: track mode 1: pulse mode
5-7	<i>not used</i>	—

represented by the majority of the outputs of three flip-flops. The flip-flops on *Beetle* can be categorised into two groups:

Clocked flip-flops They are used in the control logic which operates with the sampling clock frequency of 40 MHz in case of the *FastControl* and the I²C-clock of 100 kHz in case of the *Slow Control*.

Static flip-flops They form the bias and configuration registers. These flip-flops use triple-redundant majority voting in combination with a self-triggered correction mechanism. The correction mechanism is controlled by the pad **EnableEDC** and in default mode (enable) a single bit errors will be automatically corrected.

An 8-bit counter is integrated in *Beetle* to indicate the number of Single Event Upsets in the bias and configuration registers. All registers, including the shift-registers *CompChTh*, *CompMask* and *TpSelect*, can increment the SEU counter. The bits used in the logic control circuits (clocked flip-flops) are *not* taken into account. The counter output is readable via the I²C-bus (cf. 4.2). The two least significant bits are additionally transferred in the header of the analogue output stream (fig. 8, S0 and S1). This allows a fast monitoring of SEUs during readout. An I²C-write access to the counter register resets it.

Table 13: Bit assignment of a read access to the comparator threshold register *CompChTh*.

Bit	Function	Description
4-0	CompChTh	Comparator channel threshold number
7-5	RevId	<i>Beetle</i> chip version number 111: <i>Beetle1.3</i> 100: <i>Beetle1.4</i> 101: <i>Beetle1.5</i> (cf. section 6)

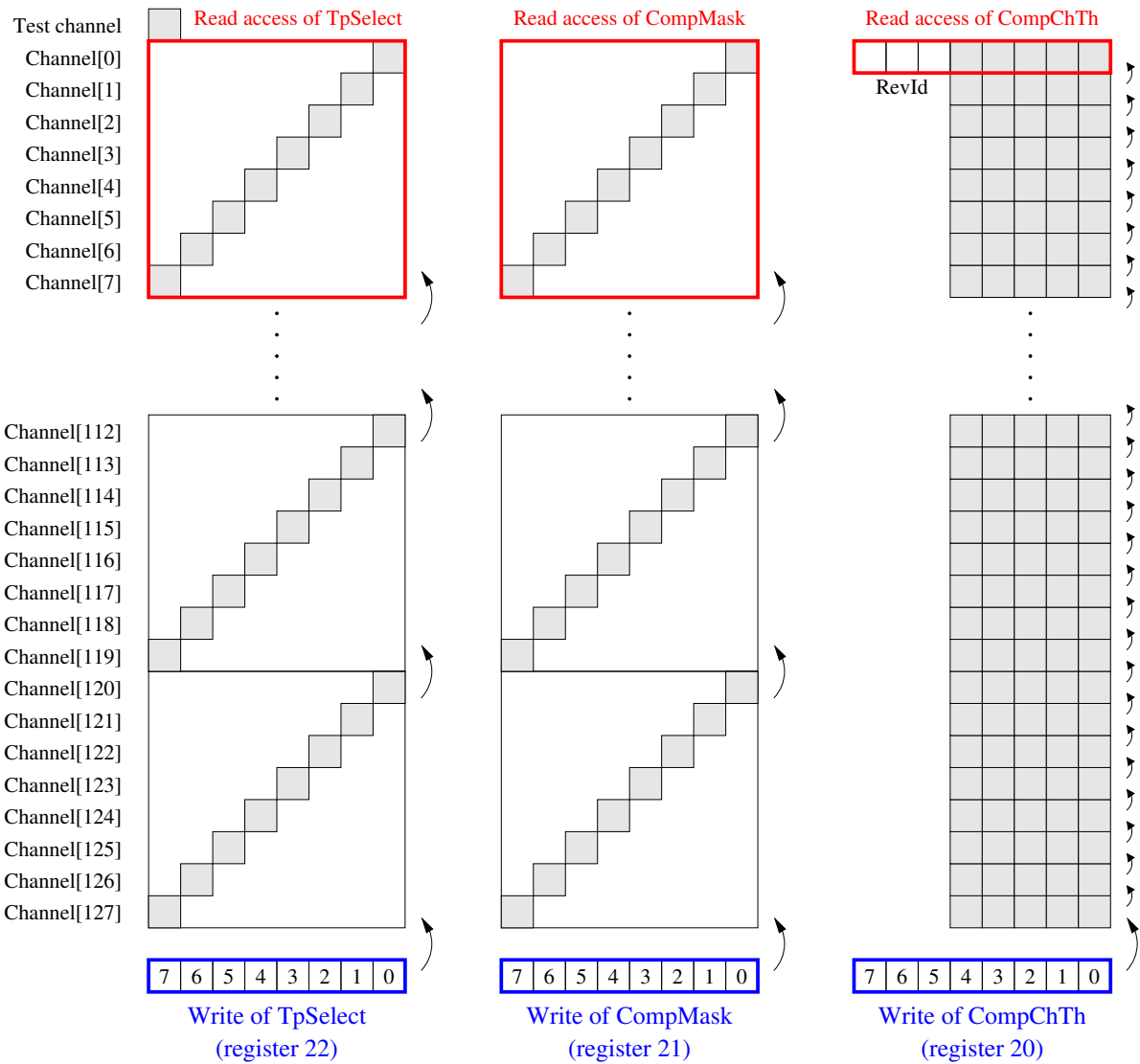


Figure 16: Mapping of shift register *TpSelect*, *CompMask* and *CompChTh*. Write access via I²C starting from the largest channel number, whereas a read access returns the data content of the lowest channel.

Table 14: Bias and configuration registers of *Beetle*.

Reg. no.	Reg. Name	Range	Res. of LSB	Nominal Setting		Description
				Value	Reg. content	
0	<i>Itp</i>	0 - 2 mA	7.8 μ A	0 μ A	0x00	test pulse bias current
1	<i>Ipre</i>	0 - 2 mA	7.8 μ A	600 μ A	0x4C	preamplifier bias current
2	<i>Isha</i>	0 - 2 mA	7.8 μ A	80 μ A	0x0A	shaper bias current
3	<i>Ibuf</i>	0 - 2 mA	7.8 μ A	80 μ A	0x0A	front-end buffer bias current
4	<i>Vfp</i>	0 - 2.5 V	9.8 mV	0 mV	0x00	preamplifier feedback voltage
5	<i>Vfs</i>	0 - 2.5 V	9.8 mV	0 mV	0x00	shaper feedback voltage
6	<i>Icomp</i>	0 - 2 mA	7.8 μ A	40 μ A	0x05	comparator bias current
7	<i>Ithdelta</i>	0 - 2 mA	7.8 μ A	—	—	current defining incremental comparator threshold
8	<i>Ithmain</i>	0 - 2 mA	7.8 μ A	—	—	current defining common comparator threshold
9	<i>Vrc</i>	0 - 1.25 V	4.9 mV	0 mV	0x00	comparator RC time constant
10	<i>Ipipe</i>	0 - 2 mA	7.8 μ A	100 μ A	0x0D	pipeamp bias current
11	<i>Vd</i>	0 - 2.5 V	9.8 mV	1 275 mV	0x82	pipeamp reset potential
12	<i>Vdcl</i>	0 - 2.5 V	9.8 mV	1 030 mV	0x69	pipeamp reference voltage
13	<i>Ivltbuf</i>	0 - 2 mA	7.8 μ A	160 μ A	0x14	pipeamp buffer bias current
14	<i>Isf</i>	0 - 2 mA	7.8 μ A	200 μ A	0x1A	multiplexer buffer bias current
15	<i>Icurrbuf</i>	0 - 2 mA	7.8 μ A	800 μ A	0x66	output buffer bias current
16	<i>Latency</i>	10 - 160	—	160	0xA0	trigger latency
17	<i>ROCtrl</i>	—	—	cf. table 11		readout control
18	<i>RclkDiv</i>	0 - 255	—	0	0x00	ratio between Rclk and Sclk
19	<i>CompCtrl</i>	—	—	cf. table 12		comparator control
20	<i>CompChTh</i>	0 - 31	—	—	—	comparator channel threshold shift register implementation and <i>Beetle</i> revision Id. (cf. table 13)
21	<i>CompMask</i>	—	—	0	0x00	comparator mask shift register implementation
22	<i>TpSelect</i>	—	—	0	0x00	test pulse selection shift register implementation
23	<i>SEUcounts</i>	0 - 255	—	—	—	sum of Single Event Upsets

5 How to get the *Beetle* Chip working

This section describes important steps to get the *Beetle* chip working. Some may be trivial, but ignoring them can cause lengthy trouble in debugging the setup.

Power and Blocking

- Power the chip:
 - for analogue operation (like VELO, ST):
connect to Vdd: pad no.: 3, 4, 135, 136, 169, 205 – 207. In case of *Beetle1.3/1.4* also 141, 240 resp. 140, 241 for *Beetle1.5*
connect to Gnd: pad no.: 1, 2, 5, 137, 138, 170, 202 – 204. In case of *1.3/1.4* also 140, 241
 - for binary/comparator operation (like PUS, RICH) connect *additionally* to the above listed pads:
to Vdd: pad no.: 142, 164, 221, 239. In case of *Beetle1.5* also 141, 240
to Gnd: pad no.: 143, 165, 220, 238. In case of *1.5* also 139, 242

In case of non-operating in binary/comparator mode, it is recommended to connect all power pads of this mode to Gnd.

- Block the following pads with $\mathcal{O}(100\text{ nF})$ to ground:
 - `Icurrbuf` (pad no. 208)
 - `Isf` (pad no. 209)
 - `Ipipe` (pad no. 210)
 - `Vdclbuf` (pad no. 211)
 - `Vdbuf` (pad no. 212)

Minimum number of pads to be bonded

The following list specifies the minimum number of *input ports* to be bonded for proper chip operation in addition to power and blocking pads:

- `Trigger` (pad no. 173, 174),
- `Clock` (pad no. 175, 176),
- `Reset` (pad no. 179, 180),
- `SCL`, `SDA` (pad no. 190, 191).

Besides the analogue output ports `AnalogOut<i>` (pad no. 194 – 201) or the comparator output ports `CompOut<i>` (pad no. 149 – 164, 222 – 237), it is recommended to bond the *digital output pads* listed in 3.9.

LVDS ports

Apply defined levels to all LVDS input ports, e.g. *Clock*, *Trigger*, *Reset*, *Testpulse*, i.e. do not leave any input pads floating.

Keep in mind that *Reset* and *Trigger* are sampled internally to the negative edge of *Clock*.

Power-up reset

Connect the `PowerupReset` port (pad no. 192) with $\mathcal{O}(100\text{ nF})$ to ground.

If after powering up the chip the power consumption decreases after programming all bias registers via I²C-interface then it is obvious that the `PowerupReset` doesn't work. Possible reasons:

- Time constant and therefore the capacitance of `Powerupreset` is too small
- Capacitance `PowerupReset` is still loaded from a previous powering. Perhaps implement a high ohmic path $\mathcal{O}(10\text{ M}\Omega)$ parallel to the capacitance to Gnd.

I²C-bus

- Define the chip ID via the pads `I2CAddr[6:0]` for individual chip access, or use general call mode. The chip responds to addresses in the range 8 – 119.
- Assure, that different chips sharing one I²C-bus line have unique addresses.
- Assure, that the `Reset` port has a defined logic level and does not change while programming the chip via I²C-bus.

FastControl

- Define the chip as *DaisyFirst* as well as *DaisyLast* (`ROCtrl` register is `XXX11XXX`).
- A change of the content of the *Latency* register (register ID 16) is taken over by the logic circuit only after applying an external reset via the `Reset` port. To check the *physical* latency, determine the time distance of the `WriteMon` (pad no. 171) and `TrigMon` (pad no. 170) signals, which is *Latency* + 1.
 \leadsto *Latency* has to be in the range 10 – 160 for proper chip operation.

Shift registers

For a correct programming of all single bits, grouped together to a shift registers, the following number of I²C-write cycles are necessary:

- *CompChTh* (reg. no. 20): 128
- *CompMask* (reg. no. 21): 16
- *TpSelect* (reg. no. 22): 17 (16 for all 128 channels and 1 for the test channel)

Of course the same number of cycles has to be applied for clearing all bits. (cf. section 4.2 and especially fig. 16)

6 Known Problems and Limitations

Problem Parity of pipeline column number (only in *Beetle1.3*)

In case of operating the *Beetle* in readout mode *Analogue readout on 4 ports* (cf. 3.5) and *Rclk divider* ratio of 1 (cf. 4.2, *RclDiv* = 0), the parity bit in the header of a consecutive readout is encoded incorrect.

Limitation Daisy chain

The readout of a second chip in a daisy chain starts too early.

Limitation *Rclk divider* ratio unequal 1

The last channels of each analogue readout sequence on each readout port is only valid for one *Sc1k* cycle. For the remaining readout time the value is undefined.

Problem Even/Odd channel crosstalk

There is a signal crosstalk in the order of 2.5% of an odd channel into the predecessor channel, and from an even channel into the successor channel on *Beetle1.3*. On *Beetle1.4* and *1.5* this crosstalk is suppressed to less than 1%.

Since the *dummy channel* of the *Beetle* is the successor channel of the *test channel*, this leads also to a baseline jump if a signal is coupled into the *test channel*.

Problem *Beetle* chip version number

In case of operating a *Beetle1.5* chip without powering the comparator (especially *VddaComp*), the read back of the *Beetle* chip version number (register 20 – *CompChTh*) via I²C will show a wrong version number.

A Pad Description

A reference number has been assigned to each pad. The numbering starts in the upper left corner of the die (with the analogue input pads left) and runs counter-clockwise (cf. figure 17 for *Beetle1.3 / 1.4* or figure 18 for *Beetle1.5*). The following tables summarise the signals and explain them. The pad coordinates refer to the lower left corner of the pad opening, which is $120\ \mu\text{m} \times 95\ \mu\text{m}$ in case of the front pads and $95\ \mu\text{m} \times 95\ \mu\text{m}$ for all others with exception of the backside power pads. Their enlarged pad windows are listed in section A.3. The origin of the coordinate system is defined by the lower left chip corner $(0, 0)$. The dimensions of the chip die are $5\ 400\ \mu\text{m} \times 6\ 100\ \mu\text{m}$ ⁴. The analogue input pads have a pitch of $40.24\ \mu\text{m}$, all others $115\ \mu\text{m}$.

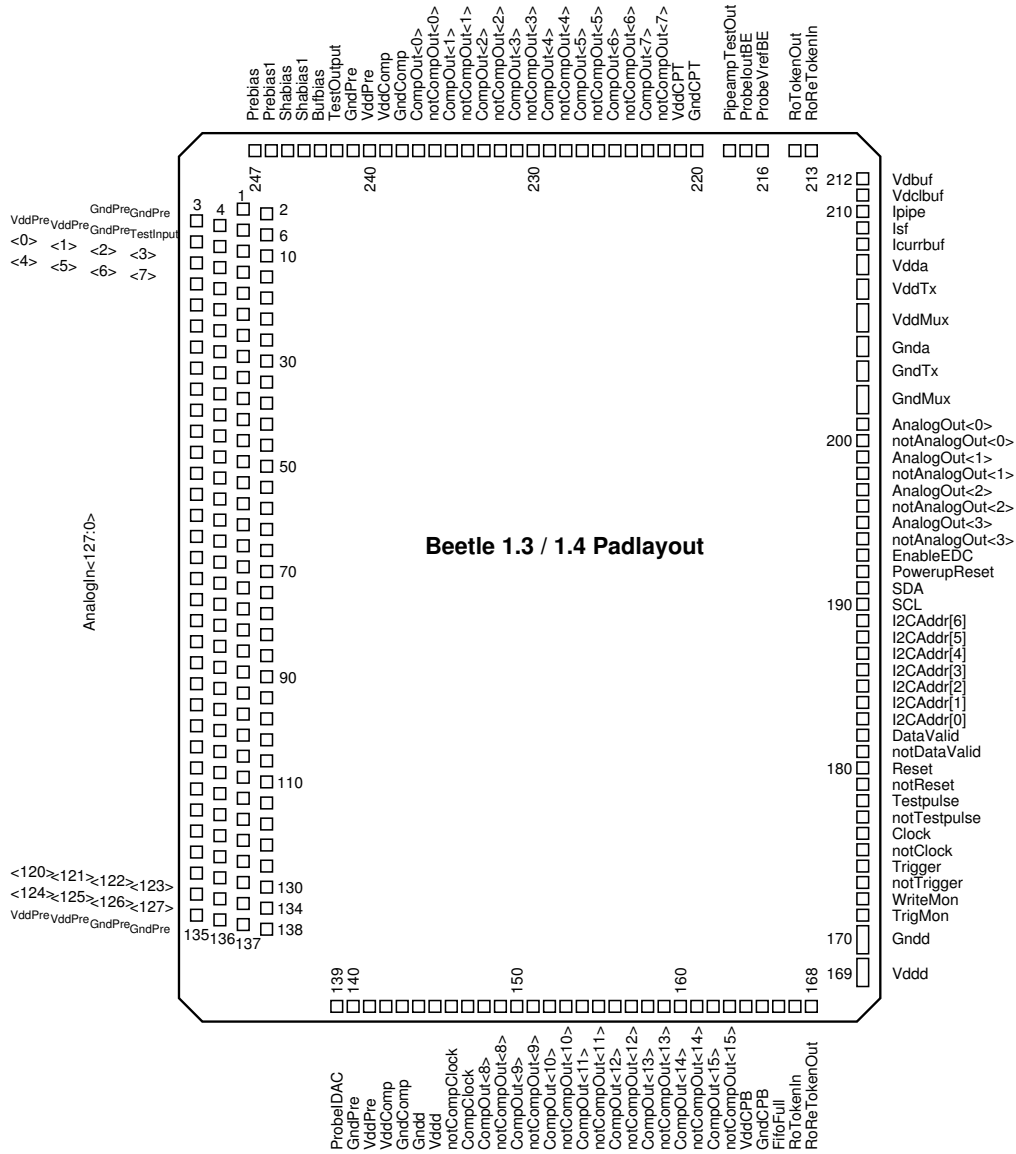


Figure 17: Pad layout of *Beetle1.3* and *Beetle1.4*. The die size is $(5.4 \times 6.1)\ \text{mm}^2$.

⁴Note, that this are the dimensions of the chip's scribe line, i.e. not including cutting margins. They could add some $100\ \mu\text{m}$ to the chip dimensions.

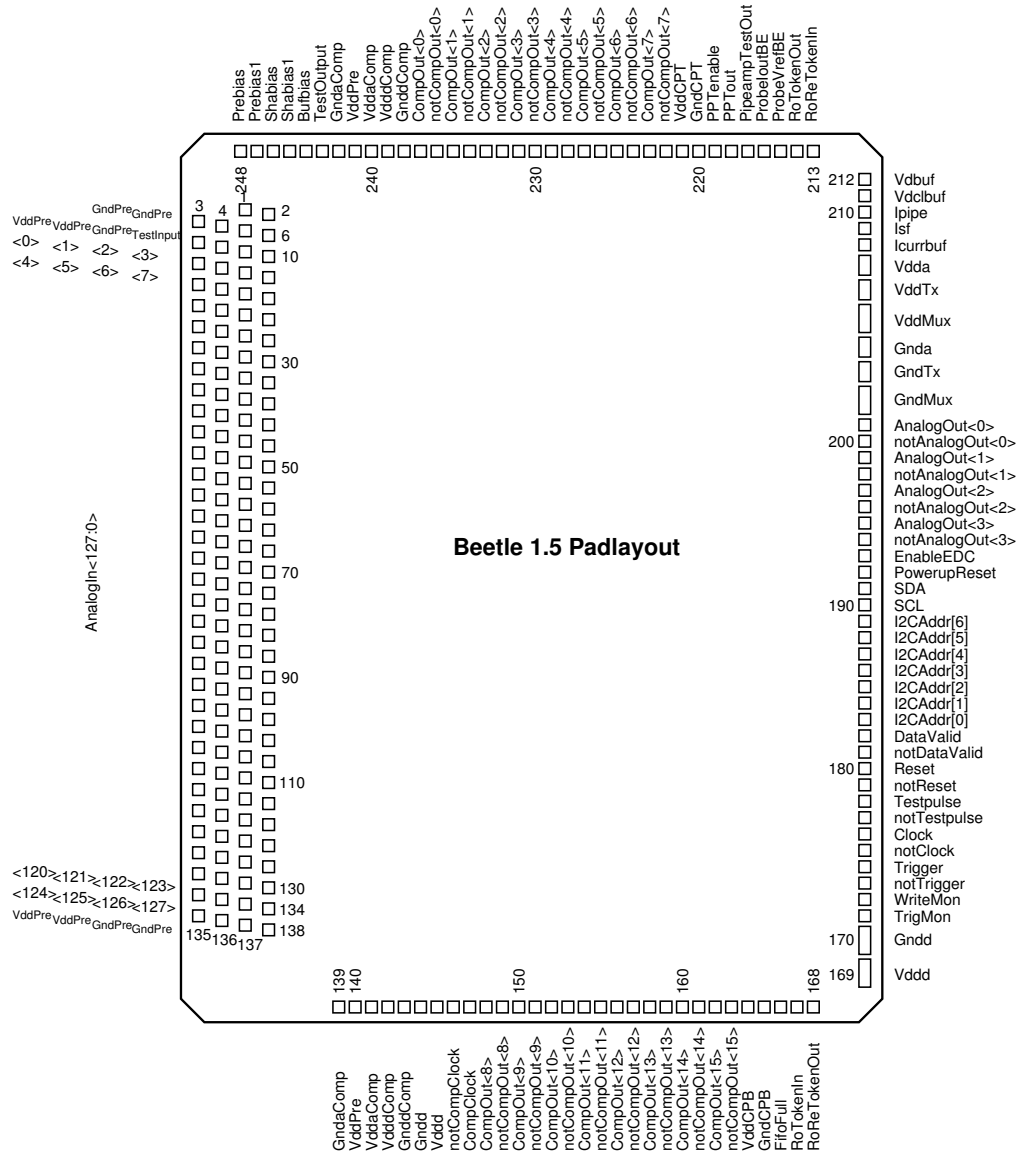


Figure 18: Pad layout of *Beetle1.5*. The die size is $(5.4 \times 6.1) \text{ mm}^2$.

A.1 Front Pads

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
1	GndPre	335.00	5876.54	power input	neg. analogue preamplifier supply (detector gnd)
2	GndPre	490.00	5836.30	power input	neg. analogue preamplifier supply (detector gnd)
3	VddPre	25.00	5796.06	power input	pos. analogue preamplifier supply
4	VddPre	180.00	5755.82	power input	pos. analogue preamplifier supply
5	GndPre	335.00	5715.58	power input	neg. analogue preamplifier supply (detector gnd)
6	TestInput	490.00	5675.34	input	input of test channel
7	AnalogIn<0>	25.00	5635.10	input	input of channel 0
8	AnalogIn<1>	180.00	5594.86	input	input of channel 1
9	AnalogIn<2>	335.00	5554.62	input	input of channel 2
10	AnalogIn<3>	490.00	5514.38	input	input of channel 3
11	AnalogIn<4>	25.00	5474.14	input	input of channel 4
12	AnalogIn<5>	180.00	5433.90	input	input of channel 5
13	AnalogIn<6>	335.00	5393.66	input	input of channel 6
14	AnalogIn<7>	490.00	5353.42	input	input of channel 7
15	AnalogIn<8>	25.00	5313.18	input	input of channel 8
16	AnalogIn<9>	180.00	5272.94	input	input of channel 9
17	AnalogIn<10>	335.00	5232.70	input	input of channel 10
18	AnalogIn<11>	490.00	5192.46	input	input of channel 11
19	AnalogIn<12>	25.00	5152.22	input	input of channel 12
20	AnalogIn<13>	180.00	5111.98	input	input of channel 13
21	AnalogIn<14>	335.00	5071.74	input	input of channel 14
22	AnalogIn<15>	490.00	5031.50	input	input of channel 15
23	AnalogIn<16>	25.00	4991.26	input	input of channel 16
24	AnalogIn<17>	180.00	4951.02	input	input of channel 17
25	AnalogIn<18>	335.00	4910.78	input	input of channel 18
26	AnalogIn<19>	490.00	4870.54	input	input of channel 19
27	AnalogIn<20>	25.00	4830.30	input	input of channel 20
28	AnalogIn<21>	180.00	4790.06	input	input of channel 21
29	AnalogIn<22>	335.00	4749.82	input	input of channel 22
30	AnalogIn<23>	490.00	4709.58	input	input of channel 23
31	AnalogIn<24>	25.00	4669.34	input	input of channel 24
32	AnalogIn<25>	180.00	4629.10	input	input of channel 25
33	AnalogIn<26>	335.00	4588.86	input	input of channel 26
34	AnalogIn<27>	490.00	4548.62	input	input of channel 27
35	AnalogIn<28>	25.00	4508.38	input	input of channel 28
36	AnalogIn<29>	180.00	4468.14	input	input of channel 29
37	AnalogIn<30>	335.00	4427.90	input	input of channel 30
38	AnalogIn<31>	490.00	4387.66	input	input of channel 31
39	AnalogIn<32>	25.00	4347.42	input	input of channel 32
40	AnalogIn<33>	180.00	4307.18	input	input of channel 33
41	AnalogIn<34>	335.00	4266.94	input	input of channel 34
42	AnalogIn<35>	490.00	4226.70	input	input of channel 35
43	AnalogIn<36>	25.00	4186.46	input	input of channel 36
44	AnalogIn<37>	180.00	4146.22	input	input of channel 37
45	AnalogIn<38>	335.00	4105.98	input	input of channel 38
46	AnalogIn<39>	490.00	4065.74	input	input of channel 39
47	AnalogIn<40>	25.00	4025.50	input	input of channel 40
48	AnalogIn<41>	180.00	3985.26	input	input of channel 41

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
49	AnalogIn<42>	335.00	3945.02	input	input of channel 42
50	AnalogIn<43>	490.00	3904.78	input	input of channel 43
51	AnalogIn<44>	25.00	3864.54	input	input of channel 44
52	AnalogIn<45>	180.00	3824.30	input	input of channel 45
53	AnalogIn<46>	335.00	3784.06	input	input of channel 46
54	AnalogIn<47>	490.00	3743.82	input	input of channel 47
55	AnalogIn<48>	25.00	3703.58	input	input of channel 48
56	AnalogIn<49>	180.00	3663.34	input	input of channel 49
57	AnalogIn<50>	335.00	3623.10	input	input of channel 50
58	AnalogIn<51>	490.00	3582.86	input	input of channel 51
59	AnalogIn<52>	25.00	3542.62	input	input of channel 52
60	AnalogIn<53>	180.00	3502.38	input	input of channel 53
61	AnalogIn<54>	335.00	3462.14	input	input of channel 54
62	AnalogIn<55>	490.00	3421.90	input	input of channel 55
63	AnalogIn<56>	25.00	3381.66	input	input of channel 56
64	AnalogIn<57>	180.00	3341.42	input	input of channel 57
65	AnalogIn<58>	335.00	3301.18	input	input of channel 58
66	AnalogIn<59>	490.00	3260.94	input	input of channel 59
67	AnalogIn<60>	25.00	3220.70	input	input of channel 60
68	AnalogIn<61>	180.00	3180.46	input	input of channel 61
69	AnalogIn<62>	335.00	3140.22	input	input of channel 62
70	AnalogIn<63>	490.00	3099.98	input	input of channel 63
71	AnalogIn<64>	25.00	3059.74	input	input of channel 64
72	AnalogIn<65>	180.00	3019.50	input	input of channel 65
73	AnalogIn<66>	335.00	2979.26	input	input of channel 66
74	AnalogIn<67>	490.00	2939.02	input	input of channel 67
75	AnalogIn<68>	25.00	2898.78	input	input of channel 68
76	AnalogIn<69>	180.00	2858.54	input	input of channel 69
77	AnalogIn<70>	335.00	2818.30	input	input of channel 70
78	AnalogIn<71>	490.00	2778.06	input	input of channel 71
79	AnalogIn<72>	25.00	2737.82	input	input of channel 72
80	AnalogIn<73>	180.00	2697.58	input	input of channel 73
81	AnalogIn<74>	335.00	2657.34	input	input of channel 74
82	AnalogIn<75>	490.00	2617.10	input	input of channel 75
83	AnalogIn<76>	25.00	2576.86	input	input of channel 76
84	AnalogIn<77>	180.00	2536.62	input	input of channel 77
85	AnalogIn<78>	335.00	2496.38	input	input of channel 78
86	AnalogIn<79>	490.00	2456.14	input	input of channel 79
87	AnalogIn<80>	25.00	2415.90	input	input of channel 80
88	AnalogIn<81>	180.00	2375.66	input	input of channel 81
89	AnalogIn<82>	335.00	2335.42	input	input of channel 82
90	AnalogIn<83>	490.00	2295.18	input	input of channel 83
91	AnalogIn<84>	25.00	2254.94	input	input of channel 84
92	AnalogIn<85>	180.00	2214.70	input	input of channel 85
93	AnalogIn<86>	335.00	2174.46	input	input of channel 86
94	AnalogIn<87>	490.00	2134.22	input	input of channel 87
95	AnalogIn<88>	25.00	2093.98	input	input of channel 88
96	AnalogIn<89>	180.00	2053.74	input	input of channel 89
97	AnalogIn<90>	335.00	2013.50	input	input of channel 90
98	AnalogIn<91>	490.00	1973.26	input	input of channel 91
99	AnalogIn<92>	25.00	1933.02	input	input of channel 92
100	AnalogIn<93>	180.00	1892.78	input	input of channel 93
101	AnalogIn<94>	335.00	1852.54	input	input of channel 94

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
102	AnalogIn<95>	490.00	1812.30	input	input of channel 95
103	AnalogIn<96>	25.00	1772.06	input	input of channel 96
104	AnalogIn<97>	180.00	1731.82	input	input of channel 97
105	AnalogIn<98>	335.00	1691.58	input	input of channel 98
106	AnalogIn<99>	490.00	1651.34	input	input of channel 99
107	AnalogIn<100>	25.00	1611.10	input	input of channel 100
108	AnalogIn<101>	180.00	1570.86	input	input of channel 101
109	AnalogIn<102>	335.00	1530.62	input	input of channel 102
110	AnalogIn<103>	490.00	1490.38	input	input of channel 103
111	AnalogIn<104>	25.00	1450.14	input	input of channel 104
112	AnalogIn<105>	180.00	1409.90	input	input of channel 105
113	AnalogIn<106>	335.00	1369.66	input	input of channel 106
114	AnalogIn<107>	490.00	1329.42	input	input of channel 107
115	AnalogIn<108>	25.00	1289.18	input	input of channel 108
116	AnalogIn<109>	180.00	1248.94	input	input of channel 109
117	AnalogIn<110>	335.00	1208.70	input	input of channel 110
118	AnalogIn<111>	490.00	1168.46	input	input of channel 111
119	AnalogIn<112>	25.00	1128.22	input	input of channel 112
120	AnalogIn<113>	180.00	1087.98	input	input of channel 113
121	AnalogIn<114>	335.00	1047.74	input	input of channel 114
122	AnalogIn<115>	490.00	1007.50	input	input of channel 115
123	AnalogIn<116>	25.00	967.26	input	input of channel 116
124	AnalogIn<117>	180.00	927.02	input	input of channel 117
125	AnalogIn<118>	335.00	886.78	input	input of channel 118
126	AnalogIn<119>	490.00	846.54	input	input of channel 119
127	AnalogIn<120>	25.00	806.30	input	input of channel 120
128	AnalogIn<121>	180.00	766.06	input	input of channel 121
129	AnalogIn<122>	335.00	725.82	input	input of channel 122
130	AnalogIn<123>	490.00	685.58	input	input of channel 123
131	AnalogIn<124>	25.00	645.34	input	input of channel 124
132	AnalogIn<125>	180.00	605.10	input	input of channel 125
133	AnalogIn<126>	335.00	564.86	input	input of channel 126
134	AnalogIn<127>	490.00	524.62	input	input of channel 127
135	VddPre	25.00	484.38	power input	pos. analogue preamplifier supply
136	VddPre	180.00	444.14	power input	pos. analogue preamplifier supply
137	GndPre	335.00	403.90	power input	neg. analogue preamplifier supply (detector gnd)
138	GndPre	490.00	363.66	power input	neg. analogue preamplifier supply (detector gnd)

A.2 Bottom Pads

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
139	ProbeIDAC	1824.12	37.50	output	current DAC (<i>Ibuf</i>) probe pad
1.3/1.4	GndaComp	1824.12	37.50	power input	neg. analogue comparator supply
140	GndPre	1939.12	37.50	power input	neg. analogue preamplifier (detector gnd) and comparator supply
1.5	VddPre	1939.12	37.50	power input	pos. analogue preamplifier supply
141	VddPre	2054.12	37.50	power input	pos. analogue preamplifier and comparator supply
1.5	VddaComp	2054.12	37.50	power input	pos. analogue comparator supply
142	VdddComp	2169.12	37.50	power input	pos. digital comparator supply
143	GnndComp	2284.12	37.50	power input	neg. digital comparator supply
144	Gnnd	2399.12	37.50	power input	neg. digital supply
145	Vddd	2514.12	37.50	power input	pos. digital supply
146	notCompClock	2629.12	37.50	LVDS input	comparator clock
147	CompClock	2744.12	37.50	LVDS input	comparator clock
148	CompOut<8>	2859.12	37.50	LVDS output	comparator output channel 8
149	notCompOut<8>	2974.12	37.50	LVDS output	comparator output channel 8
150	CompOut<9>	3089.12	37.50	LVDS output	comparator output channel 9
151	notCompOut<9>	3204.12	37.50	LVDS output	comparator output channel 9
152	CompOut<10>	3319.12	37.50	LVDS output	comparator output channel 10
153	notCompOut<10>	3434.12	37.50	LVDS output	comparator output channel 10
154	CompOut<11>	3549.12	37.50	LVDS output	comparator output channel 11
155	notCompOut<11>	3664.12	37.50	LVDS output	comparator output channel 11
156	CompOut<12>	3779.12	37.50	LVDS output	comparator output channel 12
157	notCompOut<12>	3894.12	37.50	LVDS output	comparator output channel 12
158	CompOut<13>	4009.12	37.50	LVDS output	comparator output channel 13
159	notCompOut<13>	4124.12	37.50	LVDS output	comparator output channel 13
160	CompOut<14>	4239.12	37.50	LVDS output	comparator output channel 14
161	notCompOut<14>	4354.12	37.50	LVDS output	comparator output channel 14
162	CompOut<15>	4469.12	37.50	LVDS output	comparator output channel 15
163	notCompOut<15>	4584.12	37.50	LVDS output	comparator output channel 15
164	VddCPB	4699.12	37.50	power input	pos. comparator LVFS supply
165	GndCPB	4814.12	37.50	power input	neg. comparator LVDS supply
166	FifoFull	4929.12	37.50	CMOS output	indicates a full derandomising buffer
167	RoTokenIn	5044.12	37.50	CMOS input (pull-down)	readout start token in daisy-chain mode
168	RoReTokenOut	5159.12	37.50	CMOS output	return token in daisy-chain mode

A.3 Backside Pads

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
169	Vddd	5274.62	184.72	power input	pos. digital supply (pad window: $(95 \times 210) \mu\text{m}^2$)
170	Gnnd	5274.62	414.72	power input	neg. digital supply (pad window: $(95 \times 210) \mu\text{m}^2$)
171	TrigMon	5274.62	644.72	CMOS output	indicates if trigger pointer passes column 0
172	WriteMon	5274.62	759.72	CMOS output	indicates if write pointer passes column 0
173	notTrigger	5274.62	874.72	LVDS input	trigger
174	Trigger	5274.62	989.72	LVDS input	trigger
175	notClock	5274.62	1104.72	LVDS input	system clock
176	Clock	5274.62	1219.72	LVDS input	system clock
177	notTestpulse	5274.62	1334.72	LVDS input	test pulse
178	Testpulse	5274.62	1449.72	LVDS input	test pulse
179	notReset	5274.62	1564.72	LVDS input	system reset
180	Reset	5274.62	1679.72	LVDS input	system reset
181	notDataValid	5274.62	1794.72	LVDS output	indicates presence of valid data
182	DataValid	5274.62	1909.72	LVDS output	indicates presence of valid data
183	I2CAddr<0>	5274.62	2024.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 0
184	I2CAddr<1>	5274.62	2139.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 1
185	I2CAddr<2>	5274.62	2254.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 2
186	I2CAddr<3>	5274.62	2369.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 3
187	I2CAddr<4>	5274.62	2484.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 4
188	I2CAddr<5>	5274.62	2599.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 5
189	I2CAddr<6>	5274.62	2714.72	CMOS input (pull-down)	<i>Beetle</i> chip id. bit 6
190	SCL	5274.62	2829.72	CMOS input (5V)	I ² C-bus clock port
191	SDA	5274.62	2944.72	CMOS inout (5V)	I ² C-bus data port
192	PowerupReset	5274.62	3059.72	block output	block pad for powerup Reset
193	EnableEDC	5274.62	3174.72	CMOS input (pull-up)	enable Error Detection and Correction
194	notAnalogOut<3>	5274.62	3289.72	output	analogue output channel 3
195	AnalogOut<3>	5274.62	3404.72	output	analogue output channel 3
196	notAnalogOut<2>	5274.62	3519.72	output	analogue output channel 2
197	AnalogOut<2>	5274.62	3634.72	output	analogue output channel 2
198	notAnalogOut<1>	5274.62	3749.72	output	analogue output channel 1
199	AnalogOut<1>	5274.62	3864.72	output	analogue output channel 1
200	notAnalogOut<0>	5274.62	3979.72	output	analogue output channel 0
201	AnalogOut<0>	5274.62	4094.72	output	analogue output channel 0
202	GnndMux	5274.62	4209.72	power input	neg. digital MUX supply (pad window: $(95 \times 210) \mu\text{m}^2$)
203	GndaTx	5274.62	4439.72	power input	neg. supply output driver (pad window: $(95 \times 152.5) \mu\text{m}^2$)

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
204	Gnda	5274.62	4612.22	power input	neg. analogue supply (pad window: $(95 \times 152.5) \mu\text{m}^2$)
205	VdddMux	5274.62	4784.72	power input	pos. digital MUX supply (pad window: $(95 \times 210) \mu\text{m}^2$)
206	VddaTx	5274.62	5014.72	power input	pos. supply output driver (pad window: $(95 \times 152.5) \mu\text{m}^2$)
207	Vdda	5274.62	5187.22	power input	pos. analogue supply (pad window: $(95 \times 152.5) \mu\text{m}^2$)
208	Icurrbuf	5274.62	5359.72	block output	analogue probe pad (to be blocked)
209	Isf	5274.62	5474.72	block output	analogue probe pad (to be blocked)
210	Ipipe	5274.62	5589.72	block output	analogue probe pad (to be blocked)
211	Vdclbuf	5274.62	5704.72	block output	analogue probe pad (to be blocked)
212	Vdbuf	5274.62	5819.72	block output	analogue probe pad (to be blocked)

A.4 Top Pads

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
213	RoReTokenIn	5159.12	5967.52	CMOS input (pull-down)	return token in daisy-chain mode
214	RoTokenOut	5044.12	5967.52	CMOS output	readout start token in daisy-chain mode
215 1.3/1.4 1.5	— ProbeVrefBE	— 4929.12	— 5967.52	— output	— current source BE probe pad
216 1.3/1.4 1.5	ProbeVrefBE ProbeIoutBE	4814.12 4814.12	5967.52 5967.52	output output	current source BE probe pad current source BE probe pad
217 1.3/1.4 1.5	ProbeIoutBE PipeampTestOut	4699.12 4699.12	5967.52 5967.52	output output	current source BE probe pad pipeline-amplifier probe pad
218 1.3/1.4 1.5	PipeampTestOut PPTout	4584.12 4584.12	5967.52 5967.52	output output	pipeline-amplifier probe pad digital PPT test structure probe pad
219 1.3/1.4 1.5	— PPTenable	— 4469.12	— 5967.52	— CMOS input (pull-down)	— enable pad for PPT test structure
220	GndCPT	4354.12	5967.52	power input	neg. comparator LVDS supply
221	VddCPT	4239.12	5967.52	power input	pos. comparator LVDS supply
222	notCompOut<7>	4124.12	5967.52	LVDS output	comparator output channel 7
223	CompOut<7>	4009.12	5967.52	LVDS output	comparator output channel 7
224	notCompOut<6>	3894.12	5967.52	LVDS output	comparator output channel 6
225	CompOut<6>	3779.12	5967.52	LVDS output	comparator output channel 6
226	notCompOut<5>	3664.12	5967.52	LVDS output	comparator output channel 5
227	CompOut<5>	3549.12	5967.52	LVDS output	comparator output channel 5
228	notCompOut<4>	3434.12	5967.52	LVDS output	comparator output channel 4
229	CompOut<4>	3319.12	5967.52	LVDS output	comparator output channel 4
230	notCompOut<3>	3204.12	5967.52	LVDS output	comparator output channel 3
231	CompOut<3>	3089.12	5967.52	LVDS output	comparator output channel 3
232	notCompOut<2>	2974.12	5967.52	LVDS output	comparator output channel 2
233	CompOut<2>	2859.12	5967.52	LVDS output	comparator output channel 2
234	notCompOut<1>	2744.12	5967.52	LVDS output	comparator output channel 1
235	CompOut<1>	2629.12	5967.52	LVDS output	comparator output channel 1
236	notCompOut<0>	2514.12	5967.52	LVDS output	comparator output channel 0
237	CompOut<0>	2399.12	5967.52	LVDS output	comparator output channel 0
238	GnddComp	2284.12	5967.52	power input	neg. digital comparator supply
239	VdddComp	2169.12	5967.52	power input	pos. digital comparator supply
240 1.3/1.4 1.5	VddPre VddaComp	2054.12 2054.12	5967.52 5967.52	power input power input	pos. analogue preamplifier and com- parator supply pos. analogue comparator
241 1.3/1.4 1.5	GndPre VddPre	1939.12 1939.12	5967.52 5967.52	power input power input	neg. analogue preamplifier (detector gnd) and comparator supply pos. analogue preamplifier
242 1.3/1.4 1.5	TestOutput GndaComp	1824.12 1824.12	5967.52 5967.52	output power input	front-end output of test channel neg. analogue comparator supply

Ref. no	Pin name	Coordinates		Type	Description
		x [μm]	y [μm]		
243 <i>1.3/1.4</i> <i>1.5</i>	Bufbias TestOutput	1709.12 1709.12	5967.52 5967.52	output output	analogue probe pad front-end output of test channel
244 <i>1.3/1.4</i> <i>1.5</i>	Shabias1 Bufbias	1594.12 1594.12	5967.52 5967.52	output output	analogue probe pad analogue probe pad
245 <i>1.3/1.4</i> <i>1.5</i>	Shabias Shabias1	1479.12 1479.12	5967.52 5967.52	output output	analogue probe pad analogue probe pad
246 <i>1.3/1.4</i> <i>1.5</i>	Prebias1 Shabias	1364.12 1364.12	5967.52 5967.52	output output	analogue probe pad analogue probe pad
247 <i>1.3/1.4</i> <i>1.5</i>	Prebias Prebias1	1249.12 1249.12	5967.52 5967.52	output output	analogue probe pad analogue probe pad
248 <i>1.3/1.4</i> <i>1.5</i>	— Prebias	— 1134.12	— 5967.52	— output	— analogue probe pad

B Optical Alignment Markers

For an easier chip alignment on *Beetle1.4* and *Beetle1.5* two optical alignment markers were implemented on the top metal layer. Figure 19 shows the layout and the sizes of the alignment structure. The overall position of the lower left alignment corner on the *Beetle* chip (referred to the coordinate system defined in section A) are:

- $697.92\ \mu\text{m} \times 56.64\ \mu\text{m}$
- $995.98\ \mu\text{m} \times 5\ 964.32\ \mu\text{m}$

On *Beetle1.3* this alignment structure is not available.

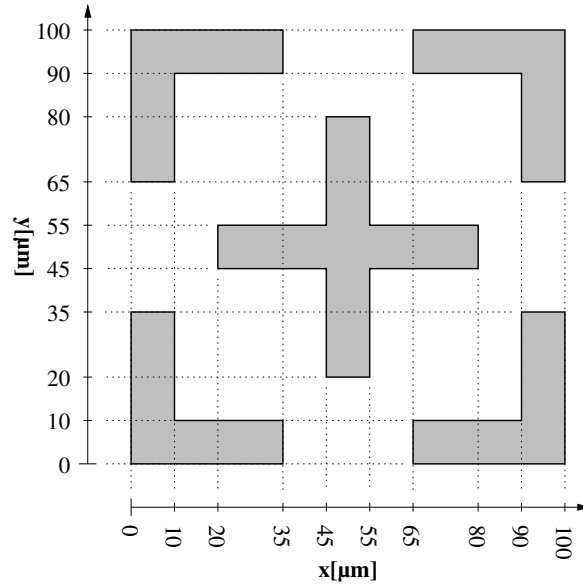


Figure 19: Optical alignment makers, available on *Beetle1.4* and *Beetle1.5*. The origin of the coordinate system is defined by the lower left alignment corner.

C Heidelberg Test Boards

For a standalone characterisation of the *Beetle* chip, i.e. without a silicon sensor connected to its inputs, a test setup consisting of two printed circuit boards has been developed in Heidelberg. This section summarises the pin configurations and bonding schemes of the two boards. The *daughter board* can carry two *Beetle* chips and is mounted on a second board, called *mother board*, which integrates the receiver circuits for the analogue output stages (fig. 3) as well as a LVDS receiver. The set-up allows the charge injection to 12 input channels per chip via a resistive voltage divider (located on the mother board) and a series capacitance. Parallel capacitances can be applied as load. Series and parallel capacitances are located on the daughter board.

Figure 20 shows the pin configuration of the daughter board, fig. 21 the layout of the top side and fig. 22 the layout of the bottom side. Figs. 23 and 24 shows the corresponding bonding schemes with and without comparator operation for a *Beetle1.3 / 1.4*, resp. figs. 25 and 26 for a *Beetle1.5*. The pin configuration of the mother board is depicted in fig. 29. A schematic diagram of the mother board is specified in fig. 30.

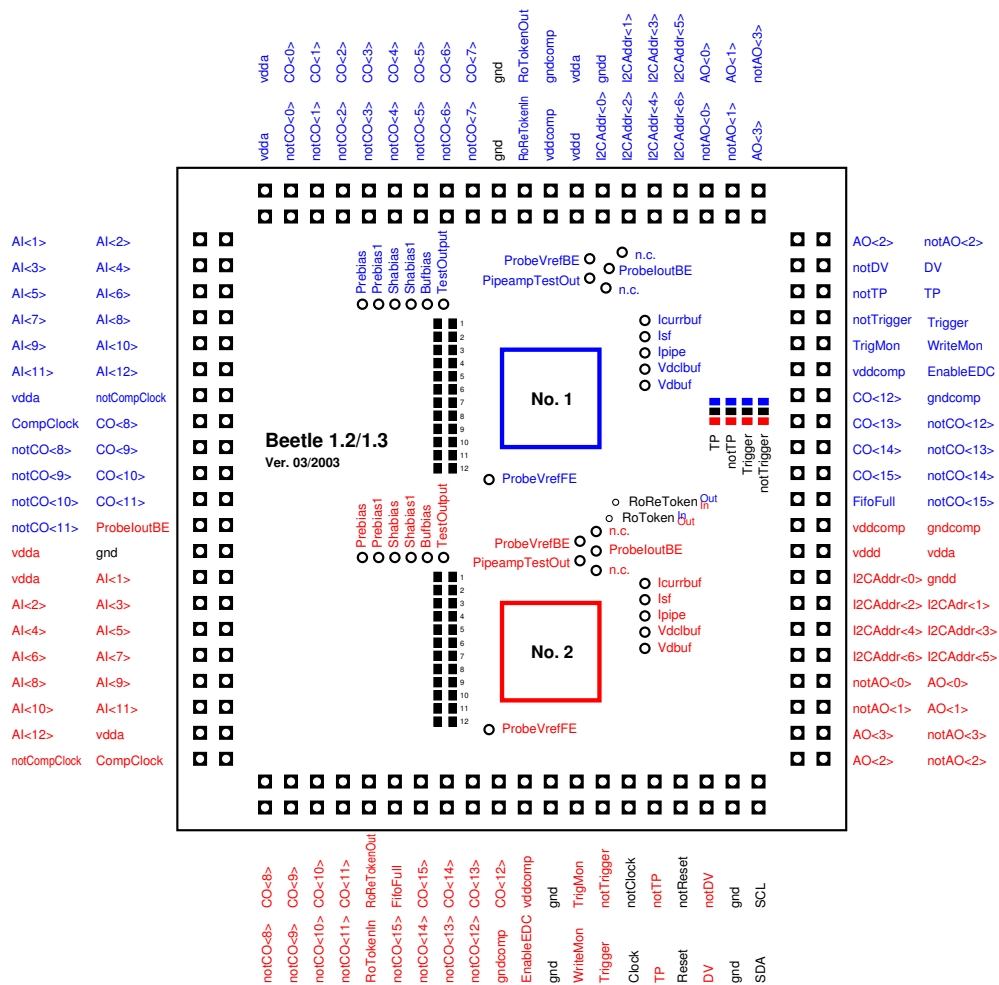


Figure 20: Pin configuration of the daughter board. The four jumper rows labelled *TP*, *notTP*, *Trigger*, *notTrigger* refer to chip no. 1 and select between the signal pins on the right side (upper position) and on the bottom side (lower position). Using the lower jumper positions, both chips receive *Trigger* and *TP* signals via the bottom side pins.

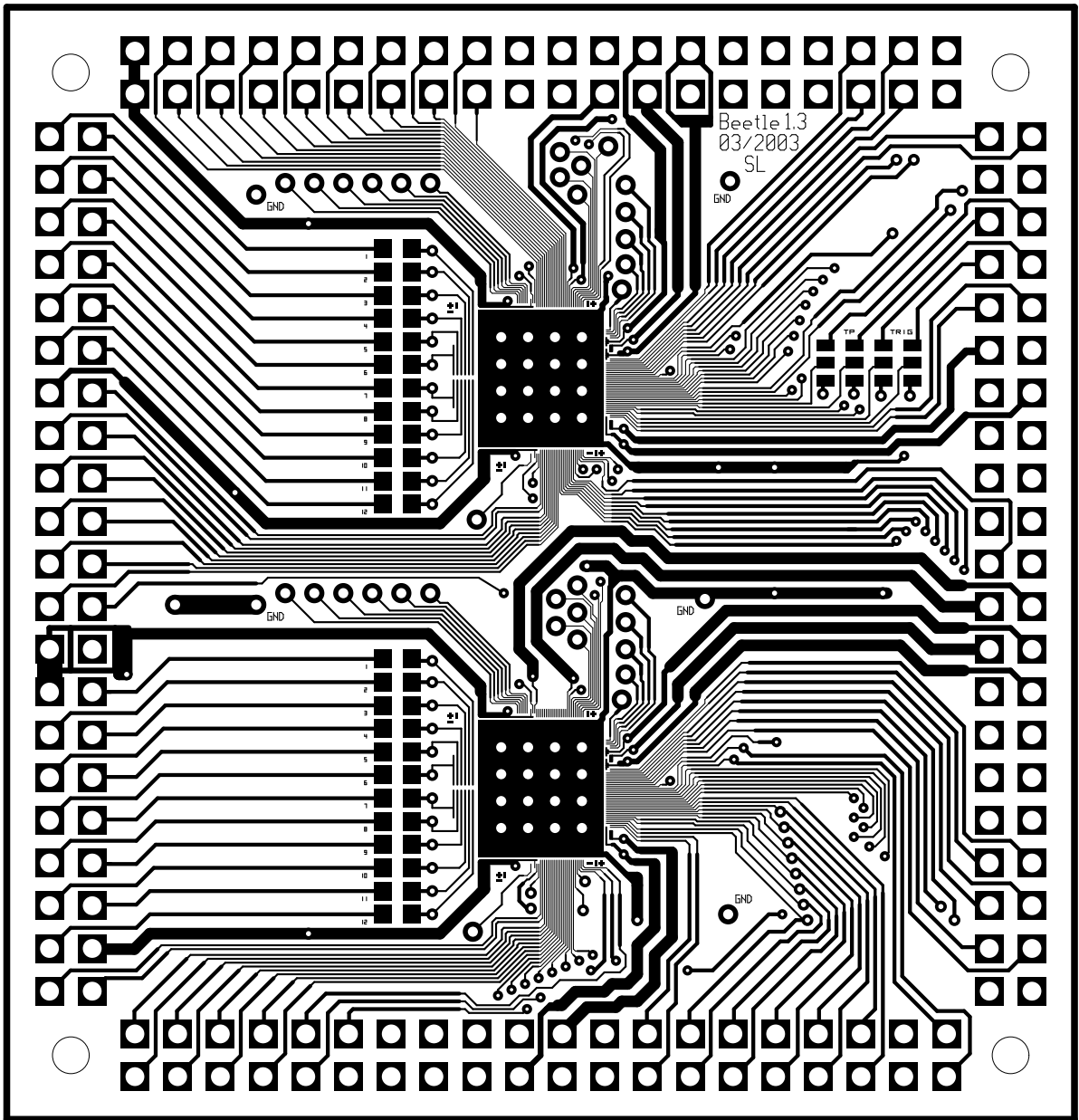


Figure 21: Top layer of the Heidelberg daughter PCB (version 03/2003).

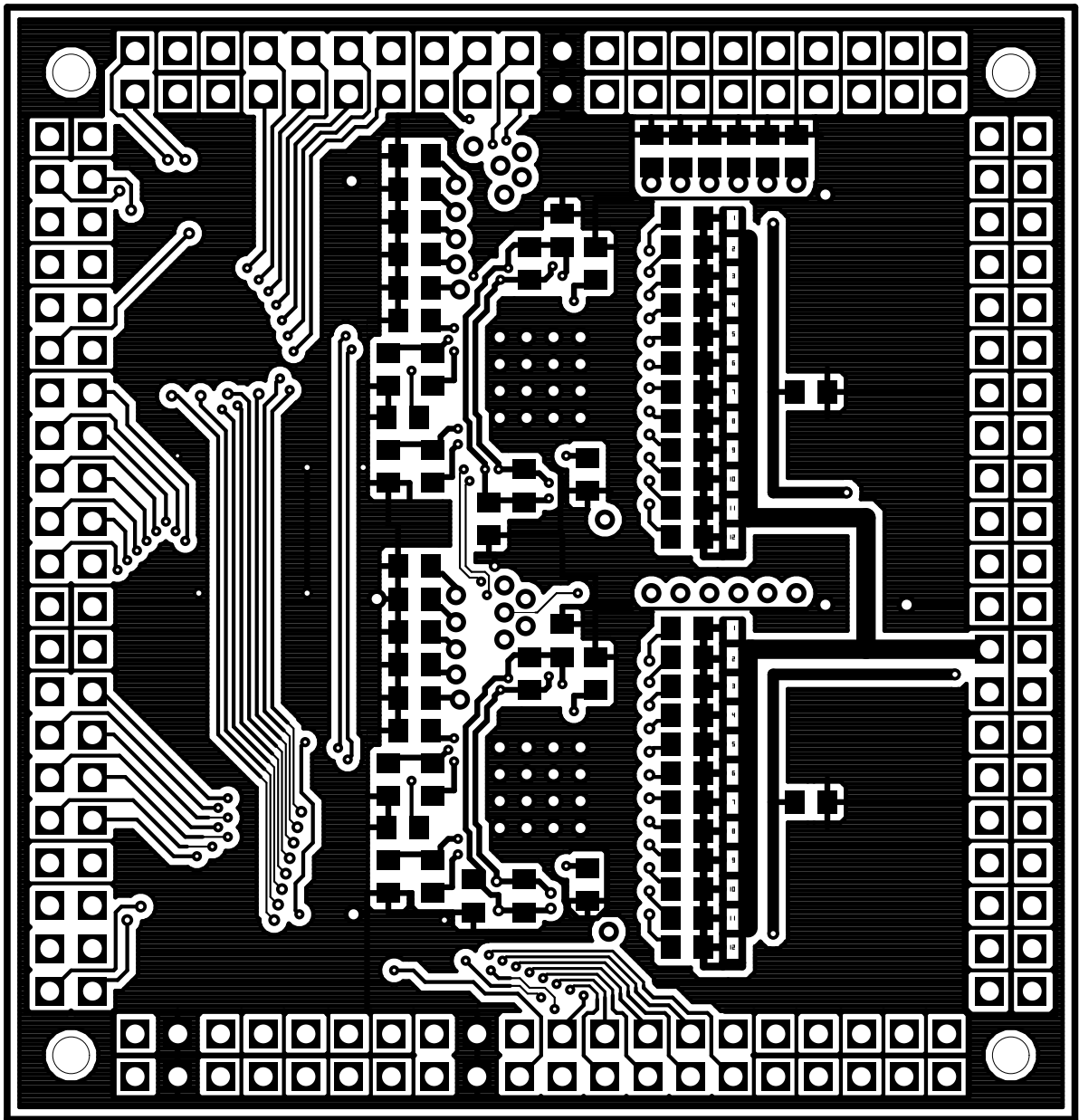


Figure 22: Bottom layer of the Heidelberg daughter PCB (version 03/2003).

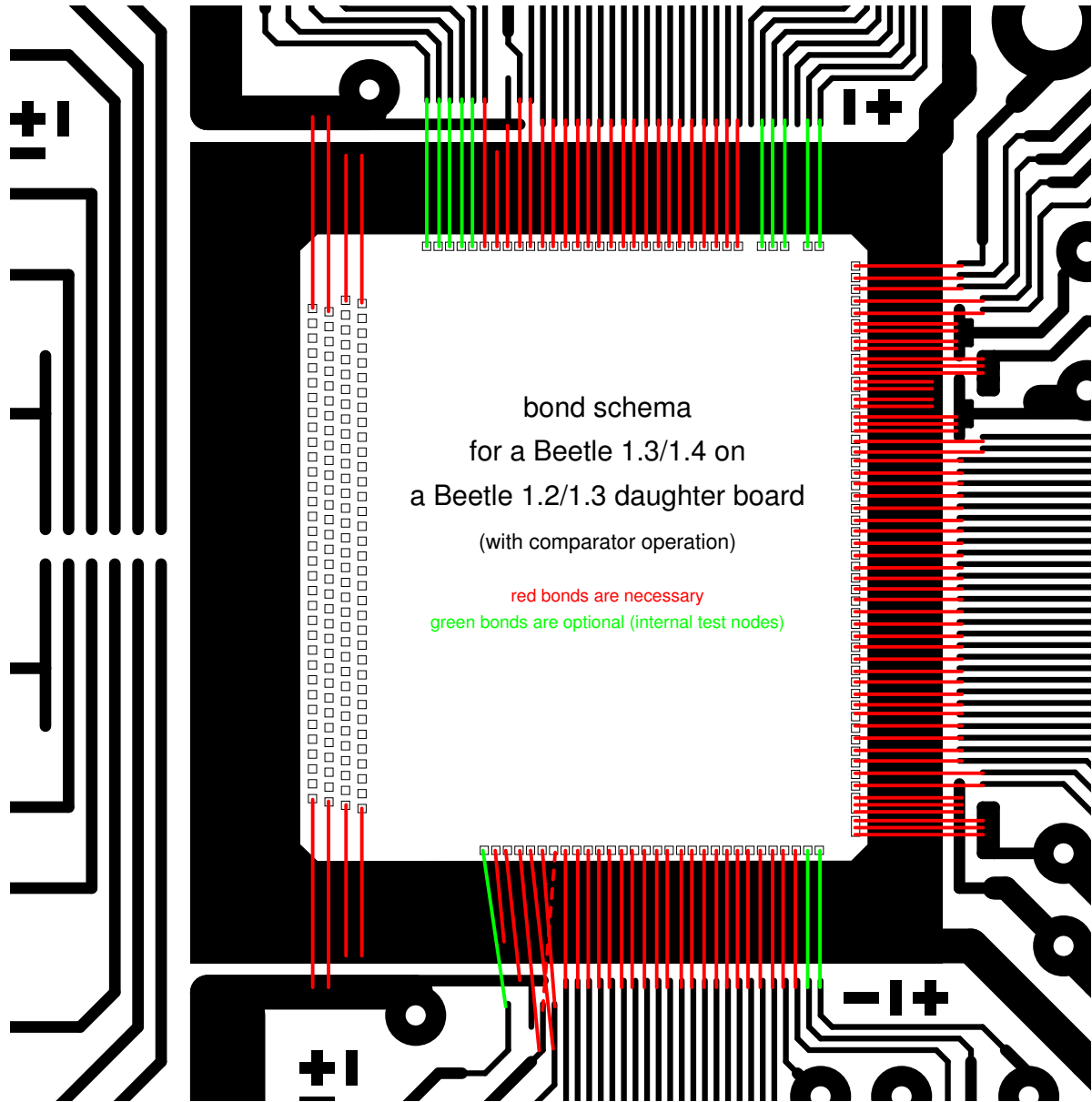


Figure 23: Bonding diagram for *Beetle1.3* and *Beetle1.4* with comparator operation.

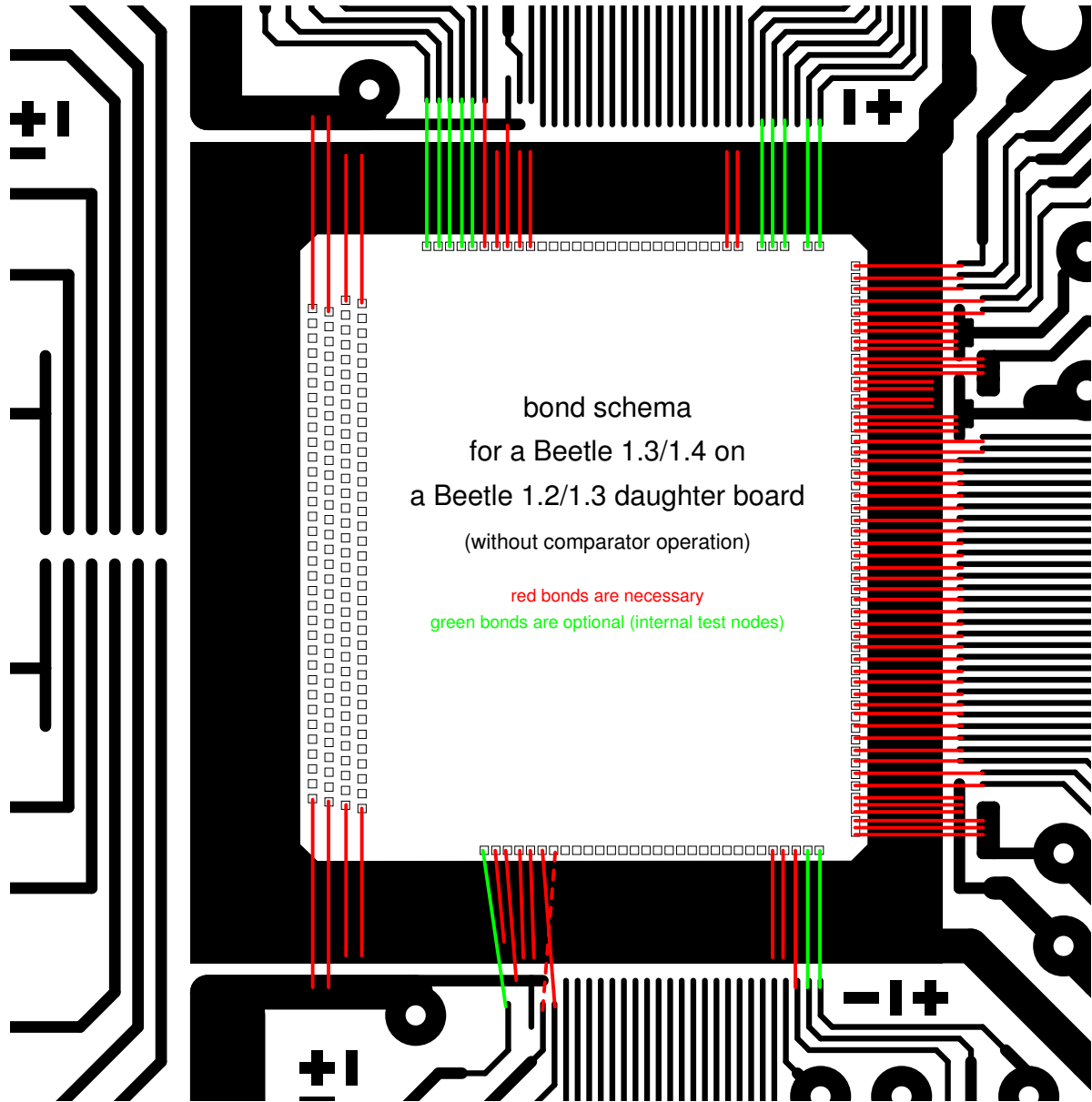


Figure 24: Bonding diagram for *Beetle1.3* and *Beetle1.4* without comparator operation.

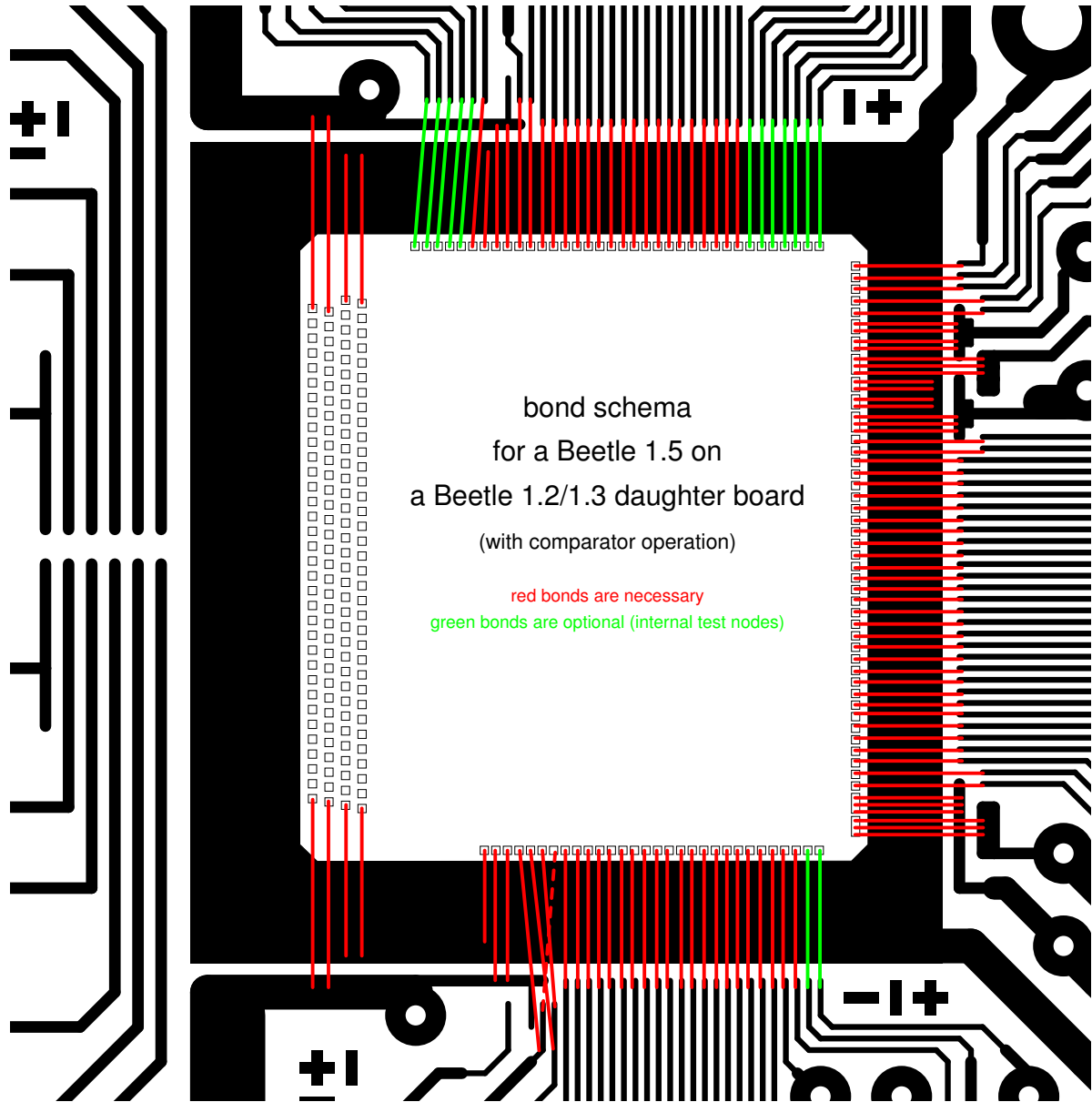


Figure 25: Bonding diagram for *Beetle1.5* with comparator operation.

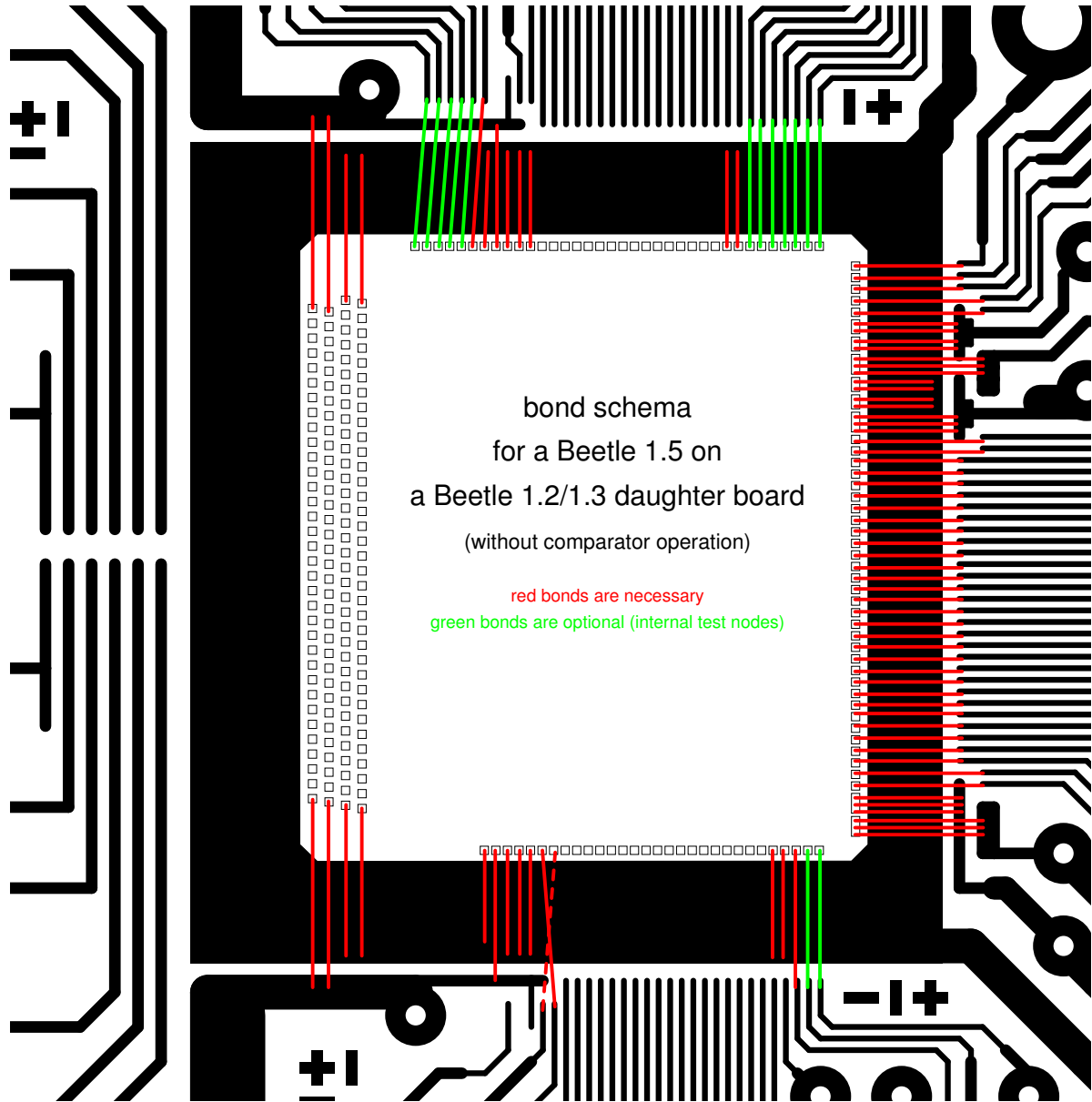


Figure 26: Bonding diagram for *Beetle1.5* without comparator operation.

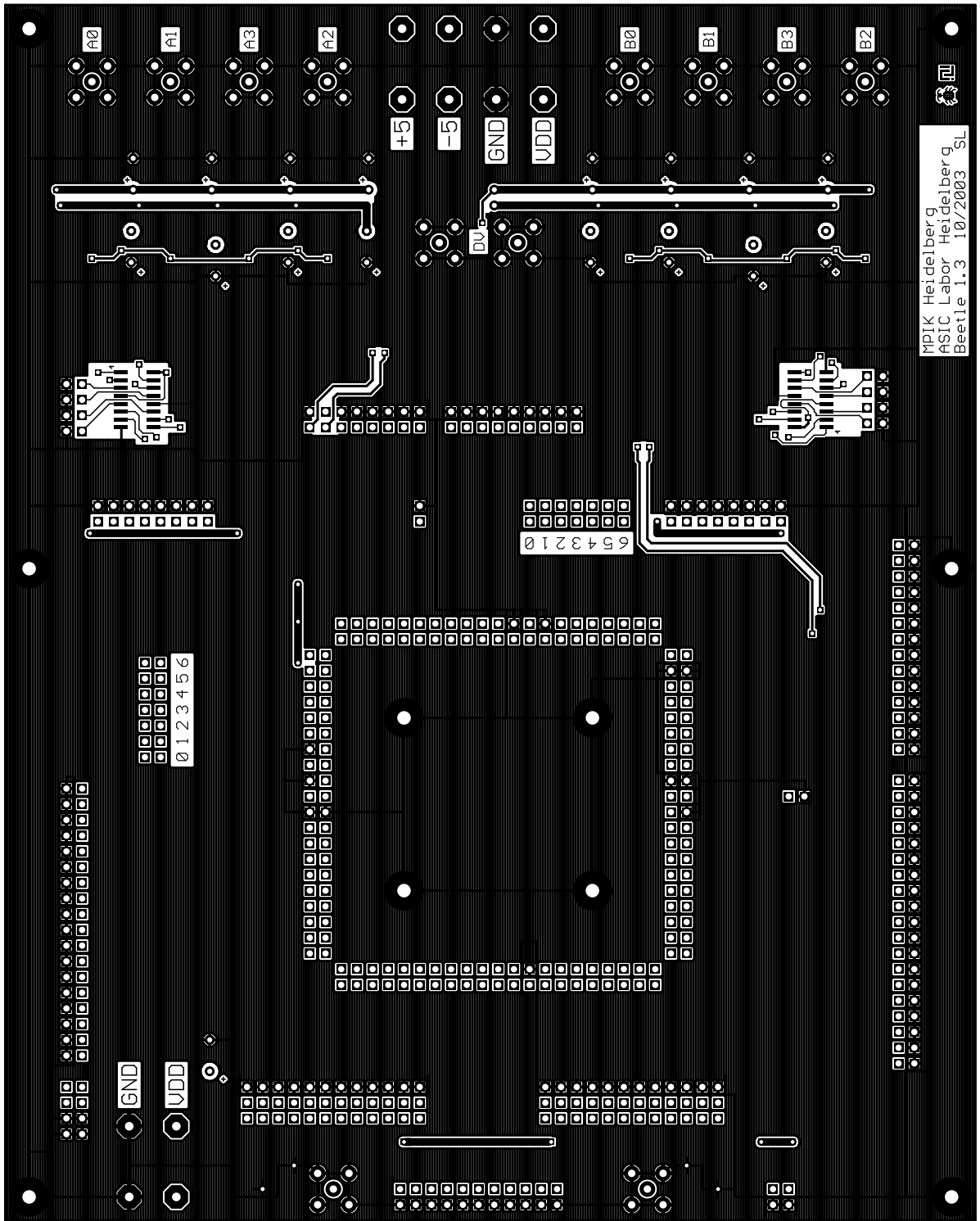


Figure 27: Top side layout of the Heidelberg mother board.

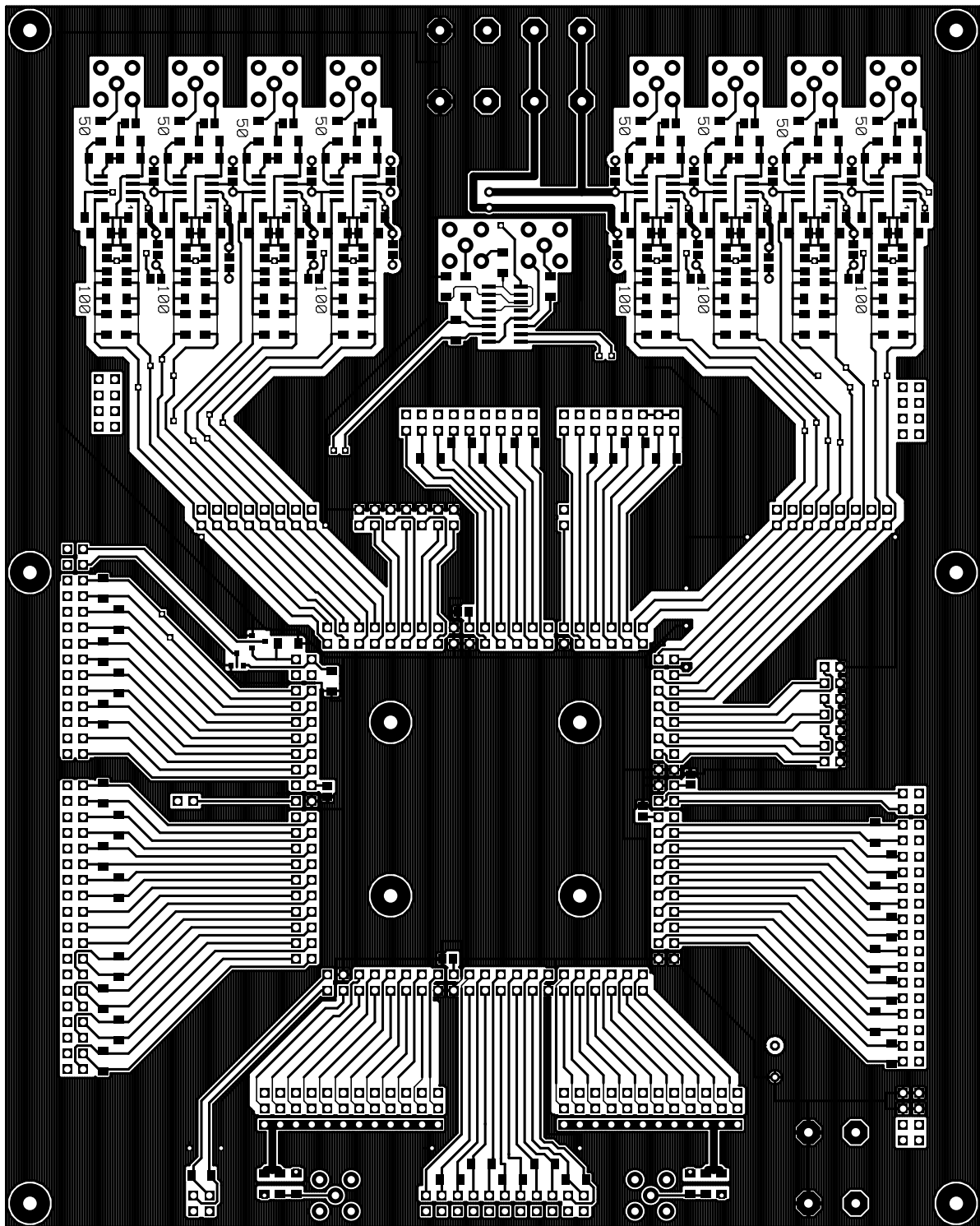


Figure 28: Bottom side layout of the Heidelberg mother board.

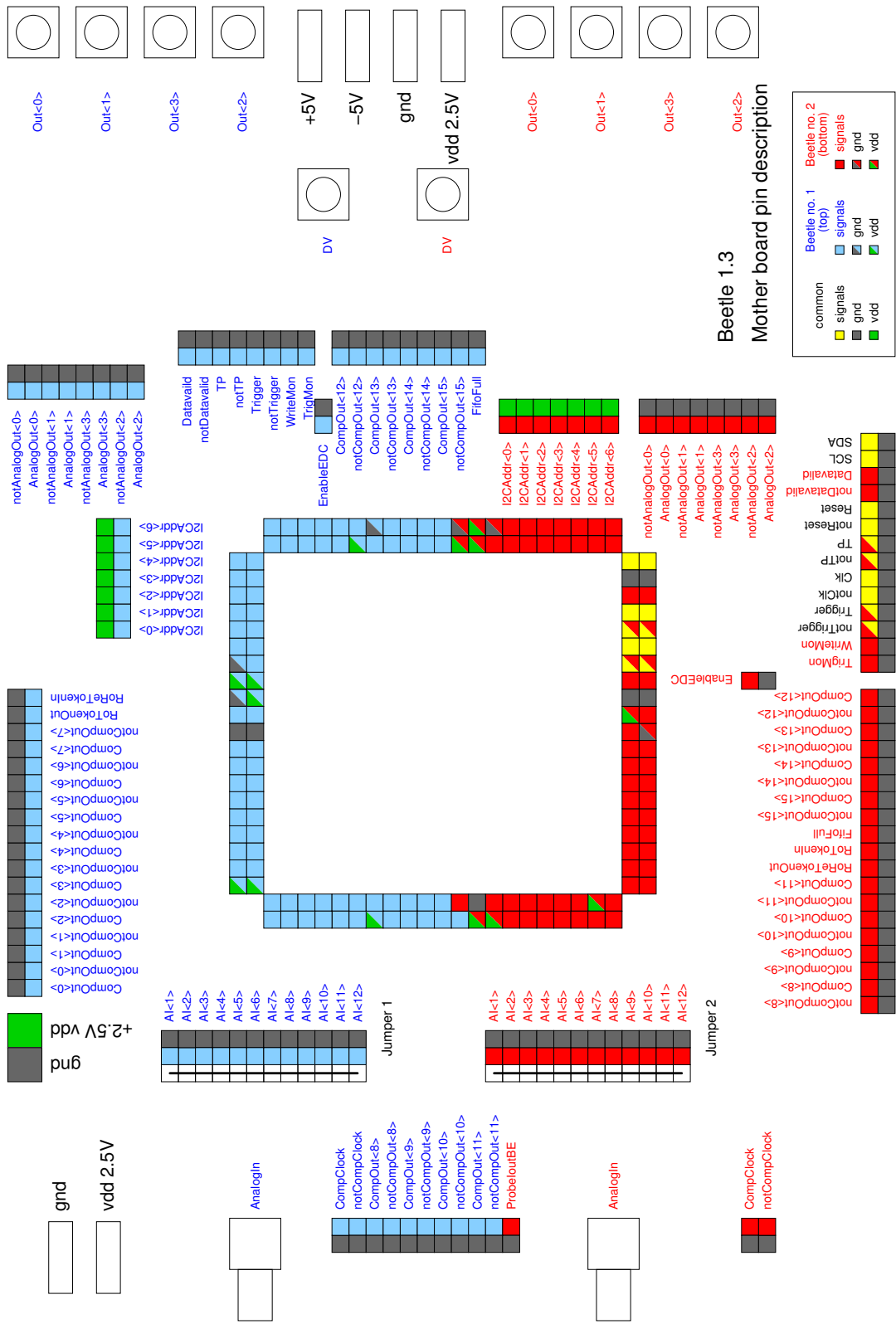


Figure 29: Pin configuration of the Heidelberg mother board.

References

- [1] R. Brenner et al., Nucl. Instr. and Meth. A339 (1994) 564
- [2] R. Brenner et al., Performance of a LHC front-end running at 67 MHz, NIM A339 (1994) 447
- [3] R. Horrisberger et al., A novel readout chip for silicon strip detectors with analogue pipeline and digitally controlled analogue processing, NIM A326 (1993) 92
- [4] AD8129/AD8130, Low-Cost 270 MHz Differential Receiver Amplifiers, Analog Devices Inc. (2001)
- [5] DS90C032, LVDS Quad CMOS Differential Line Receiver, National Semiconductor Corporation, September 22, 2003 (2003)
- [6] The I²C-bus and how to use it, Philips Semiconductors, April 1995 (1995)